

## 8-BIT SINGLE-CHIP MICROCONTROLLER

**DESCRIPTION**

The  $\mu$ PD178P018A<sup>Note</sup> is a device in which the internal mask ROM of the  $\mu$ PD178018A is replaced with a one-time PROM or EPROM.

Because this device can be programmed by users, it is ideally suited for system evaluation, small-lot and multiple-device production, and early development and time-to-market.

The  $\mu$ PD178P018A is a PROM version corresponding to the  $\mu$ PD178004A, 178006A, and 178016A.

**Note** Under development

**Caution** The  $\mu$ PD178P018AKK-T does not maintain planned reliability when used in your system's mass-produced products. Please use only experimentally or for evaluation purposes during trial manufacture.

For more information on functions, refer to the following User's Manuals. Be sure to read them when designing.

$\mu$ PD178018A Subseries User's Manual: To be prepared  
78K/0 Series User's Manual Instruction: U12326E

**FEATURES**

- Pin-compatible with mask ROM version (except for V<sub>PP</sub> pin)
- Internal PROM: 60 Kbytes
  - $\mu$ PD178P018AGC : One-time programmable (ideally suited for small-lot production)
  - $\mu$ PD178P018AKK-T: Reprogrammable (ideally suited for system evaluation)
- Internal high-speed RAM: 1 024 bytes
- Internal expansion RAM: 2 048 bytes
- Buffer RAM: 32 bytes
- Can be operated in the same power supply voltage as the mask ROM version  
(During PLL operation: V<sub>DD</sub> = 4.5 to 5.5 V)

The electrical specifications (power supply current, etc.) and PLL analog specifications of the  $\mu$ PD178P018A differ from that of mask ROM versions. So, these differences should be considered and verified before application sets are mass-produced.

In this document, the term PROM is used in parts common to one-time PROM versions and EPROM versions.

The information in this document is subject to change without notice.

**APPLICATIONS**

Car stereo, home stereo systems

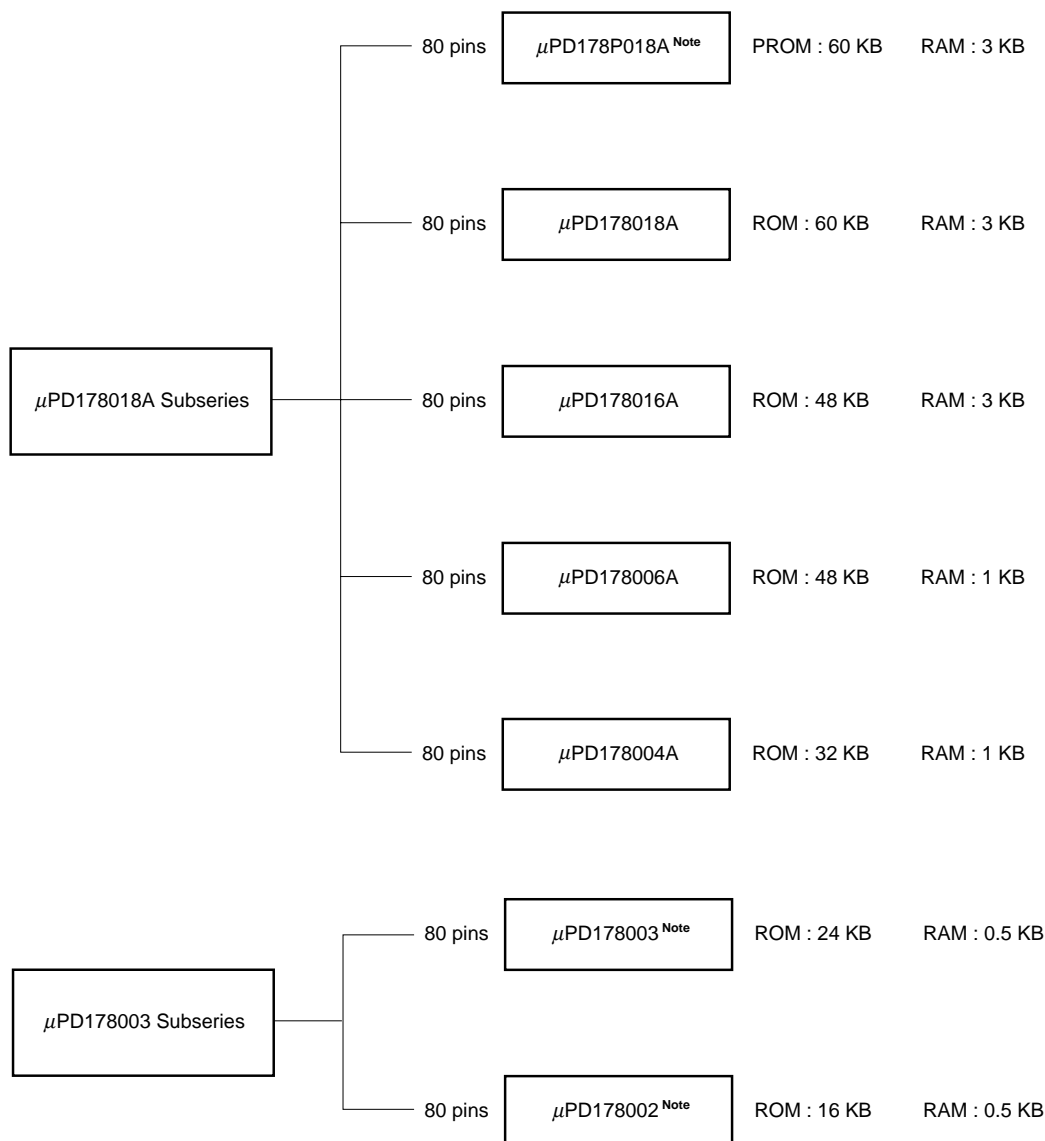
**ORDERING INFORMATION**

Part Number	Package	Internal ROM	Quality Grade
μPD178P018AGC-3B9 <sup>Note</sup>	80-pin plastic QFP (14 × 14 mm, 0.65-mm pitch)	One-Time PROM	Standard
μPD178P018AKK-T <sup>Note</sup>	80-pin ceramic WQFN (14 × 14 mm, 0.65-mm pitch)	EPROM	Not applicable

**Note** Under planning

Please refer to the **Quality grade on NEC Semiconductor Devices** (Document number C11531E) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

**μPD178018A SUBSERIES AND μPD178003 SUBSERIES EXPANSION**



**Note** Under development

FUNCTION DESCRIPTION

(1/2)

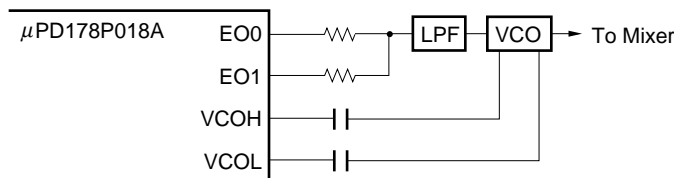
Item		Function
Internal memory		<ul style="list-style-type: none"> <li>• PROM : 60 Kbytes</li> <li>• RAM                             <ul style="list-style-type: none"> <li>High-speed RAM : 1 024 bytes</li> <li>Expansion RAM : 2 048 bytes</li> <li>Buffer RAM : 32 bytes</li> </ul> </li> </ul>
General register		8 bits × 32 registers (8 bits × 8 registers × 4 banks)
Instruction cycle		With variable instruction execution time function 0.44 μs/0.88 μs/1.78 μs/3.56 μs/7.11 μs/14.22 μs (with 4.5-MHz crystal resonator)
Instruction set		<ul style="list-style-type: none"> <li>• 16-bit operation</li> <li>• Multiply/divide (8 bits × 8 bits, 16 bits ÷ 8 bits)</li> <li>• Bit manipulate (set, reset, test, Boolean operation)</li> <li>• BCD Adjust, etc.</li> </ul>
I/O port		Total : 62 pins <ul style="list-style-type: none"> <li>• CMOS input : 1 pin</li> <li>• CMOS I/O : 54 pins</li> <li>• N-ch open-drain I/O : 4 pins</li> <li>• N-ch open-drain output : 3 pins</li> </ul>
A/D converter		8-bit resolution × 6 channels
Serial interface		<ul style="list-style-type: none"> <li>• 3-wire/SBI/2-wire/I<sup>2</sup>C bus <b>Note</b> mode selectable : 1 channel</li> <li>• 3-wire serial I/O mode (with automatic transmit/receive function of up to 32 bytes): 1 channel</li> </ul>
Timer		<ul style="list-style-type: none"> <li>• Basic timer (timer carry FF (10 Hz)) : 1 channel</li> <li>• 8-bit timer/event counter : 2 channels</li> <li>• 8-bit timer (D/A converter: PWM output): 1 channel</li> <li>• Watchdog timer : 1 channel</li> </ul>
Buzzer (BEEP) output		1.5 kHz, 3 kHz, 6 kHz
Vectored interrupt source	Maskable	Internal: 8, external: 7
	Non-maskable	Internal: 1
	Software	Internal: 1
Test input		Internal: 1

**Note** When using the I<sup>2</sup>C bus mode (including when this mode is implemented by program without using the peripheral hardware), consult your local NEC sales representative when you place an order for mask.

(2/2)

Item		Function
PLL frequency synthesizer	Division mode	Two types <ul style="list-style-type: none"> <li>• Direct division mode (VCOL pin)</li> <li>• Pulse swallow mode (VCOH and VCOL pins)</li> </ul>
	Reference frequency	7 types selectable by program (1, 3, 5, 9, 10, 25, 50 kHz)
	Charge pump	Error out output: 2 (EO0 and EO1 pins <b>Note 1</b> )
	Phase comparator	Unlock detectable by program
Frequency counter		<ul style="list-style-type: none"> <li>• Frequency measurement                             <ul style="list-style-type: none"> <li>• AMIFC pin: for 450-kHz count</li> <li>• FMIFC pin: for 450-kHz/10.7-MHz count</li> </ul> </li> </ul>
D/A converter (PWM output)		8-/9-bit resolution × 3 channels (shared by 8-bit timer)
Standby function		<ul style="list-style-type: none"> <li>• HALT mode</li> <li>• STOP mode</li> </ul>
Reset		<ul style="list-style-type: none"> <li>• Reset via the RESET pin</li> <li>• Internal reset by watchdog timer</li> <li>• Reset by power-ON clear circuit (3-value detection)                             <ul style="list-style-type: none"> <li>• Detection of less than 4.5 V <b>Note 2</b> (CPU clock: <math>f_x</math>)</li> <li>• Detection of less than 3.5 V <b>Note 2</b> (CPU clock: <math>f_x/2</math> or less and on power application)</li> <li>• Detection of less than 2.5 V <b>Note 2</b> (in STOP mode)</li> </ul> </li> </ul>
Power supply voltage		<ul style="list-style-type: none"> <li>• <math>V_{DD} = 4.5</math> to <math>5.5</math> V (with PLL operating)</li> <li>• <math>V_{DD} = 3.5</math> to <math>5.5</math> V (with CPU operating, CPU clock: <math>f_x/2</math> or less)</li> <li>• <math>V_{DD} = 4.5</math> to <math>5.5</math> V (with CPU operating, CPU clock: <math>f_x</math>)</li> </ul>
Package		<ul style="list-style-type: none"> <li>• 80-pin plastic QFP (14 × 14 mm, 0.65-mm pitch)</li> <li>• 80-pin ceramic WQFN (14 × 14 mm, 0.65-mm pitch)</li> </ul>

**Notes 1.** The EO1 pin can be set to high impedance for the μPD178P018A. The following figure shows an application example.



LPF : Low path filter  
 VCO : Voltage controlled oscillator

- To lock to a target frequency at high speed  
 Setting the EO0 and EO1 pins to error out output improves the output current potential and LPF voltage control potential.
  - Normal state  
 Setting only the EO0 pin to error out output maintains the LPF stable.
- 2.** These voltage values are maximum values. Reset is actually executed at a voltage lower than these values.

**PIN CONFIGURATIONS (TOP VIEW)**

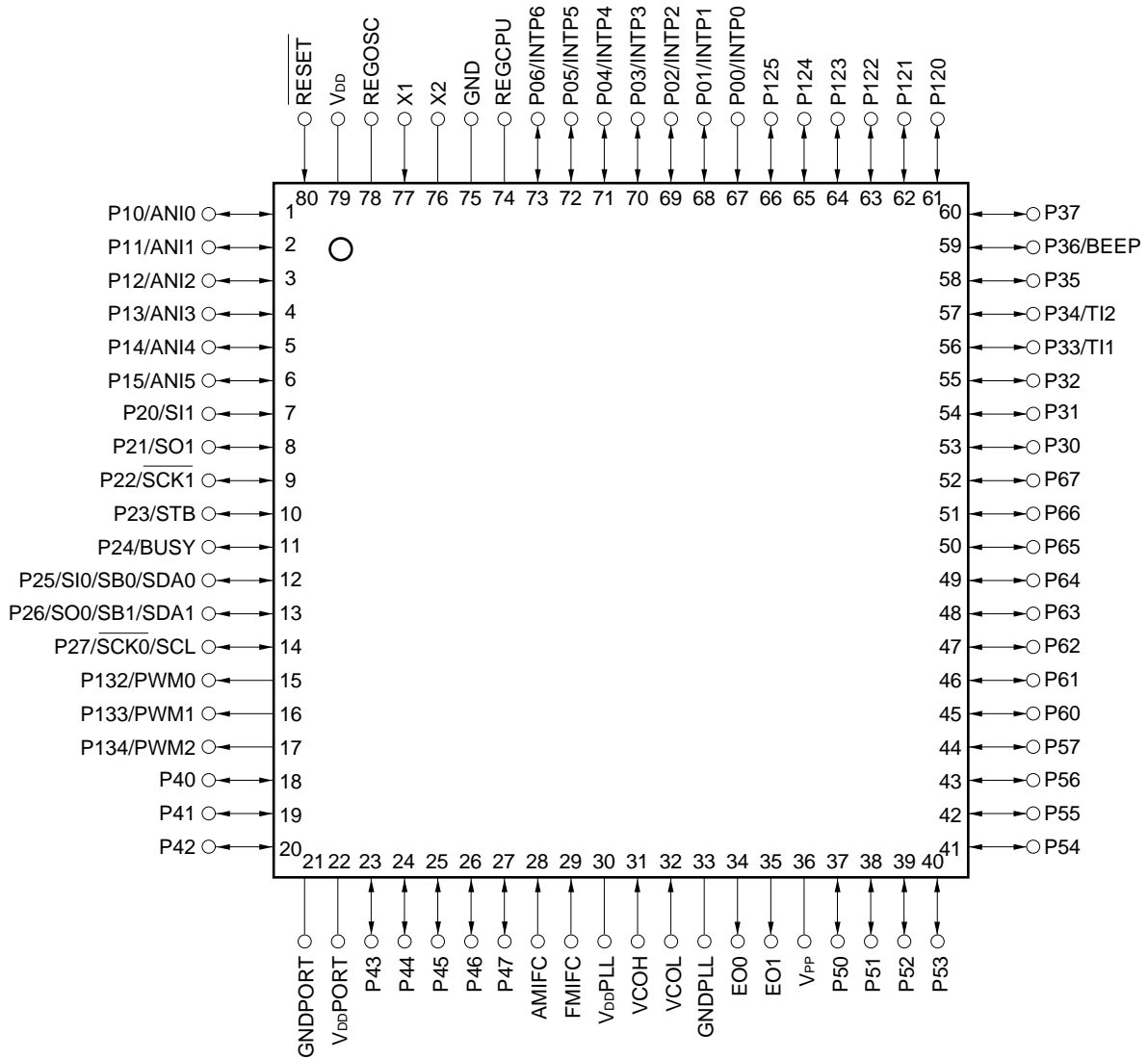
**(1) Normal operating mode**

- **80-PIN PLASTIC QFP (14 × 14 mm, 0.65-mm pitch)**

μPD178P018AGC-3B9 Note

- **80-PIN CERAMIC WQFN (14 × 14 mm, 0.65-mm pitch)**

μPD178P018AKK-T Note



**Note** Under development

- Cautions**
1. Connect the V<sub>PP</sub> pin to GND directly.
  2. Connect the V<sub>DD</sub>PORT and V<sub>DD</sub>PLL pins to V<sub>DD</sub>.
  3. Connect the GNDPORT and GNDPLL pins to GND.
  4. Connect each of the REGOSC and REGCPU pins to GND via a 0.1-μF capacitor.

AMIFC	: AM Intermediate Frequency Counter Input	PWM0 to PWM2	: PWM Output
ANI0 to ANI5	: A/D Converter Input	REGCPU	: Regulator for CPU Power Supply
BEEP	: Buzzer Output	REGOSC	: Regulator for Oscillator
BUSY	: Busy Output	$\overline{\text{RESET}}$	: Reset Input
EO0, EO1	: Error Out Output	SB0, SB1	: Serial Data Bus Input/Output
FMIFC	: FM Intermediate Frequency Counter Input	$\overline{\text{SCK0}}, \overline{\text{SCK1}}$	: Serial Clock Input/Output
GND	: Ground	SCL	: Serial Clock Input/Output
GNDPLL	: PLL Ground	SDA0, SDA1	: Serial Data Input/Output
GNDPORT	: Port Ground	SI0, SI1	: Serial Data Input
INTP0 to INTP6	: Interrupt Inputs	SO0, SO1	: Serial Data Output
P00 to P06	: Port 0	STB	: Strobe Output
P10 to P15	: Port 1	TI1, TI2	: Timer Clock Input
P20 to P27	: Port 2	VCOL, VCOH	: Local Oscillation Input
P30 to P37	: Port 3	V <sub>DD</sub>	: Power Supply
P40 to P47	: Port 4	V <sub>DD</sub> PLL	: PLL Power Supply
P50 to P57	: Port 5	V <sub>DD</sub> PORT	: Port Power Supply
P60 to P67	: Port 6	V <sub>PP</sub>	: Programming Power Supply
P120 to P125	: Port 12	X1, X2	: Crystal Resonator Connection
P132 to P134	: Port 13		

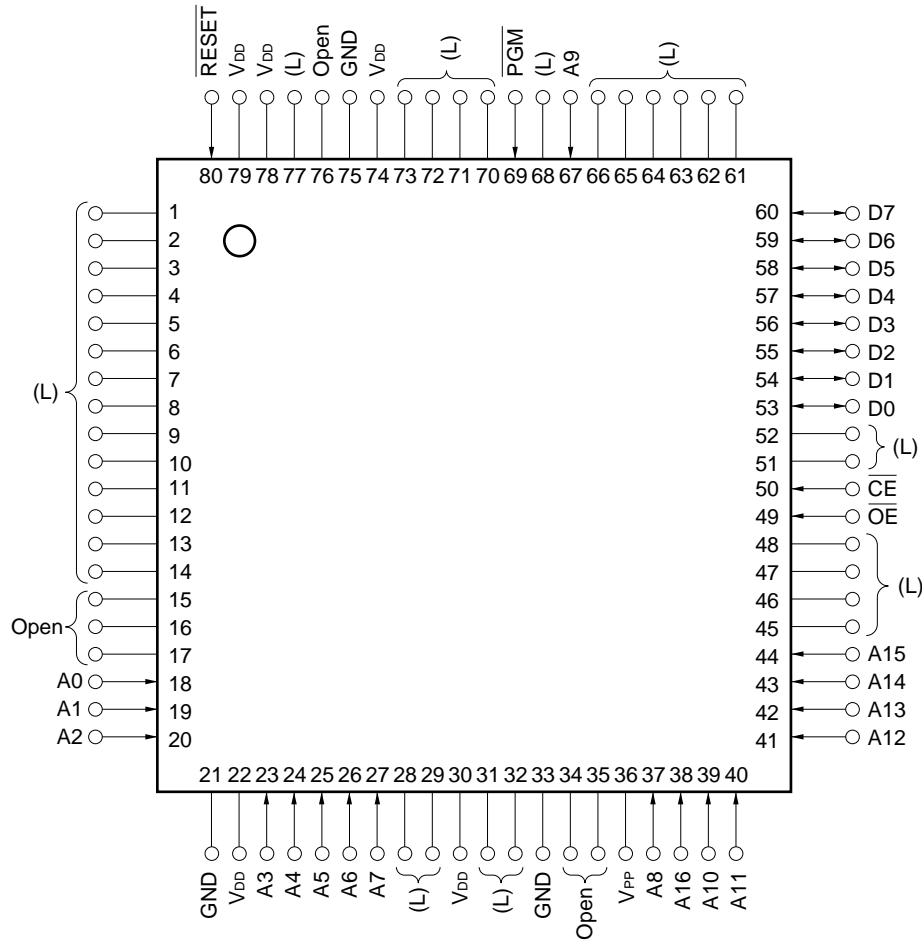
(2) PROM programming mode

- 80-PIN PLASTIC QFP (14 × 14 mm)

μPD178P018AGC-3B9 <sup>Note</sup>

- 80-PIN CERAMIC WQFN

μPD178P018AKK-T <sup>Note</sup>



**Note** Under planning

- Cautions**
1. (L) : Individually connect to GND via a pull-down resistor.
  2. GND : Connect to GND.
  3. RESET : Set to the low level.
  4. Open : Leave open.

A0 to A16 : Address Bus

CE : Chip Enable

D0 to D7 : Data Bus

GND : Ground

OE : Output Enable

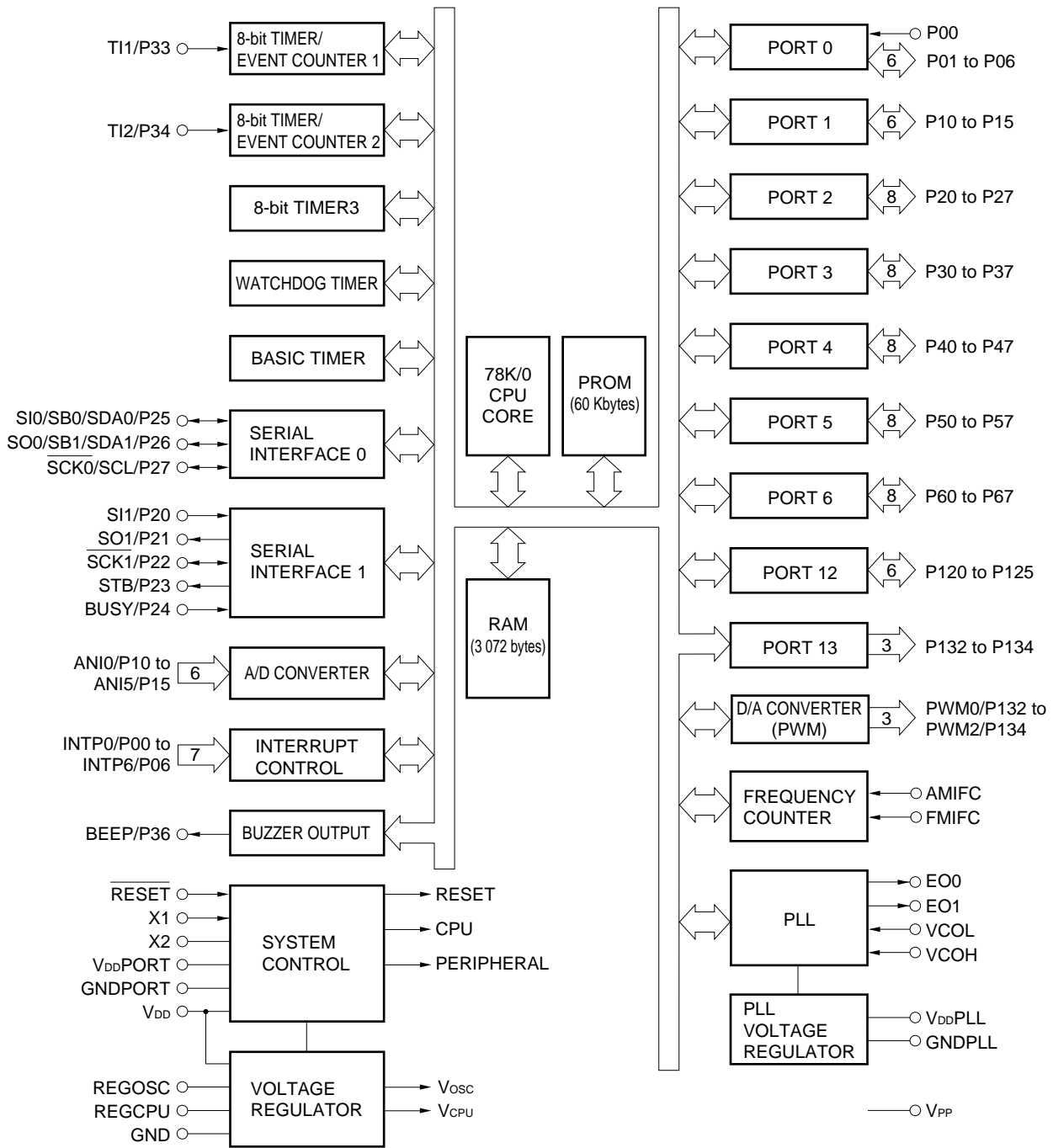
PGM : Program

RESET : Reset

VDD : Power Supply

VPP : Programming Power Supply

BLOCK DIAGRAM





## CONTENTS

1. PIN FUNCTION LIST .....	10
1.1 Pins in Normal Operating Mode .....	10
1.2 Pins in PROM Programming Mode .....	12
1.3 Pins Input/Output Circuits and Recommended Connection of Unused Pins .....	13
2. PROM PROGRAMMING .....	16
2.1 Operating Modes .....	16
2.2 PROM Write Procedure .....	18
2.3 PROM Read Procedure .....	22
3. PROGRAM ERASURE ( $\mu$ PD178P018AKK-T ONLY) .....	23
4. OPAQUE FILM ON ERASURE WINDOW ( $\mu$ PD178P018AKK-T ONLY) .....	23
5. ONE-TIME PROM VERSION SCREENING .....	23
6. ELECTRICAL SPECIFICATIONS (PRELIMINARY) .....	24
7. PACKAGE DRAWINGS .....	46
APPENDIX A. DIFFERENCES BETWEEN $\mu$ PD178018A AND $\mu$ PD178018 SUBSERIES .....	48
APPENDIX B. DEVELOPMENT TOOLS .....	49
APPENDIX C. RELATED DOCUMENTS .....	53

1. PIN FUNCTION LIST

1.1 Pins in Normal Operating Mode

(1) Port pins

Pin Name	I/O	Function		After Reset	Alternate Function
P00	Input	Port 0.	Input only	Input	INTP0
P01 to P06	I/O	7-bit input/output port.	Input/output mode can be specified bit-wise.	Input	INTP1 to INTP6
P10 to P15	I/O	Port 1.	6-bit input/output port. Input/output mode can be specified bit-wise.	Input	ANI0 to ANI5
P20	I/O	Port 2.	8-bit input/output port. Input/output mode can be specified bit-wise.	Input	SI1
P21		SO1			
P22		SCK1			
P23		STB			
P24		BUSY			
P25		SI0/SB0/SDA0			
P26		SO0/SB1/SDA1			
P27		SCK0/SCL			
P30 to P32	I/O	Port 3.	8-bit input/output port. Input/output mode can be specified bit-wise.	Input	—
P33		TI1			
P34		TI2			
P35		—			
P36		BEEP			
P37		—			
P40 to P47	I/O	Port 4.	8-bit input/output port. Input/output mode can be specified in 8-bit units. Test input flag (KRIF) is set to 1 by falling edge detection.	Input	—
P50 to P57	I/O	Port 5.	8-bit input/output port. Input/output mode can be specified bit-wise.	Input	—
P60 to P63	I/O	Port 6.	Middle voltage N-ch open-drain input/output port. LEDs can be driven directly.	Input	—
P64 to P67		8-bit input/output port. Input/output mode can be specified bit-wise.			
P120 to P125	I/O	Port 12.	6-bit input/output port. Input/output mode can be specified bit-wise.	Input	—
P132 to P134	Output	Port 13.	3-bit output port. N-ch open-drain output port.	—	PWM0 to PWM2

(2) Non-port pins (1 of 2)

Pin Name	I/O	Function	After Reset	Alternate Function
INTP0 to INTP6	Input	External maskable interrupt inputs with specifiable valid edges (rising edge, falling edge, both rising and falling edges).	Input	P00 to P06
SI0	Input	Serial interface serial data input	Input	P25/SB0/SDA0
SI1				P20
SO0	Output	Serial interface serial data output	Input	P26/SB1/SDA1
SO1				P21
SB0	I/O	Serial interface serial data input/output	Input	P25/SI0/SDA0
SB1				P26/SO0/SDA1
SDA0				P25/SI0/SB0
SDA1				P26/SO0/SB1
$\overline{\text{SCK0}}$	I/O	Serial interface serial clock input/output	Input	P27/SCL
$\overline{\text{SCK1}}$				P22
SCL				P27/ $\overline{\text{SCK0}}$
STB	Output	Serial interface automatic transmit/receive strobe output	Input	P23
BUSY	Input	Serial interface automatic transmit busy input	Input	P24
TI1	Input	External count clock input to 8-bit timer (TM1)	Input	P33
TI2		External count clock input to 8-bit timer (TM2)		P34
BEEP	Output	Buzzer output	Input	P36
ANI0 to ANI5	Input	A/D converter analog input	Input	P10 to P15
PWM0 to PWM2	Output	PWM output	—	P132 to P134
EO0, EO1	Output	Error out output from charge pump of the PLL frequency synthesizer	—	—
VCOL	Input	Inputs PLL local band oscillation frequency (In HF, MF mode).	—	—
VCOH	Input	Inputs PLL local band oscillation frequency (In VHF mode).	—	—
AMIFC	Input	Inputs AM intermediate frequency counter.	—	—
FMIFC	Input	Inputs FM intermediate frequency counter.	—	—
$\overline{\text{RESET}}$	Input	System reset input	—	—
X1	Input	Crystal resonator connection for system clock oscillation	—	—
X2	—		—	—
REGOSC	—	Regulator for oscillator. Connected to GND via a 0.1-μF capacitor.	—	—
REGCPU	—	Regulator for CPU power supply. Connected to GND via a 0.1-μF capacitor.	—	—
V <sub>DD</sub>	—	Positive power supply	—	—
GND	—	Ground	—	—
V <sub>DD</sub> PORT	—	Positive power supply for port block	—	—
GNDPORT	—	Ground for port block	—	—
V <sub>DD</sub> PLL <sup>Note</sup>	—	Positive power supply for PLL	—	—
GNDPLL <sup>Note</sup>	—	Ground for PLL	—	—

**Note** Connect a capacitor of approximately 1 000 pF between V<sub>DD</sub>PLL pin and GNDPLL pin.

**(2) Non-port pins (2/2)**

Pin Name	I/O	Function	After Reset	Alternate Function
V <sub>PP</sub>	—	High-voltage applied during program write/verification. Connected directly to GND in normal operating mode.	—	—

**1.2 Pins in PROM Programming Mode**

Pin Name	I/O	Function
$\overline{\text{RESET}}$	Input	PROM programming mode setting When +5 V or +12.5 V is applied to V <sub>PP</sub> pin and a low-level signal is applied to the $\overline{\text{RESET}}$ pin, this chip is set in the PROM programming mode.
V <sub>PP</sub>	Input	PROM programming mode setting and high-voltage applied during program write/verification.
A0 to A16	Input	Address bus
D0 to D7	I/O	Data bus
$\overline{\text{CE}}$	Input	PROM enable input/program pulse input
$\overline{\text{OE}}$	Input	Read strobe input to PROM
$\overline{\text{PGM}}$	Input	Program/program inhibit input in PROM programming mode.
V <sub>DD</sub>	—	Positive power supply
GND	—	Ground potential

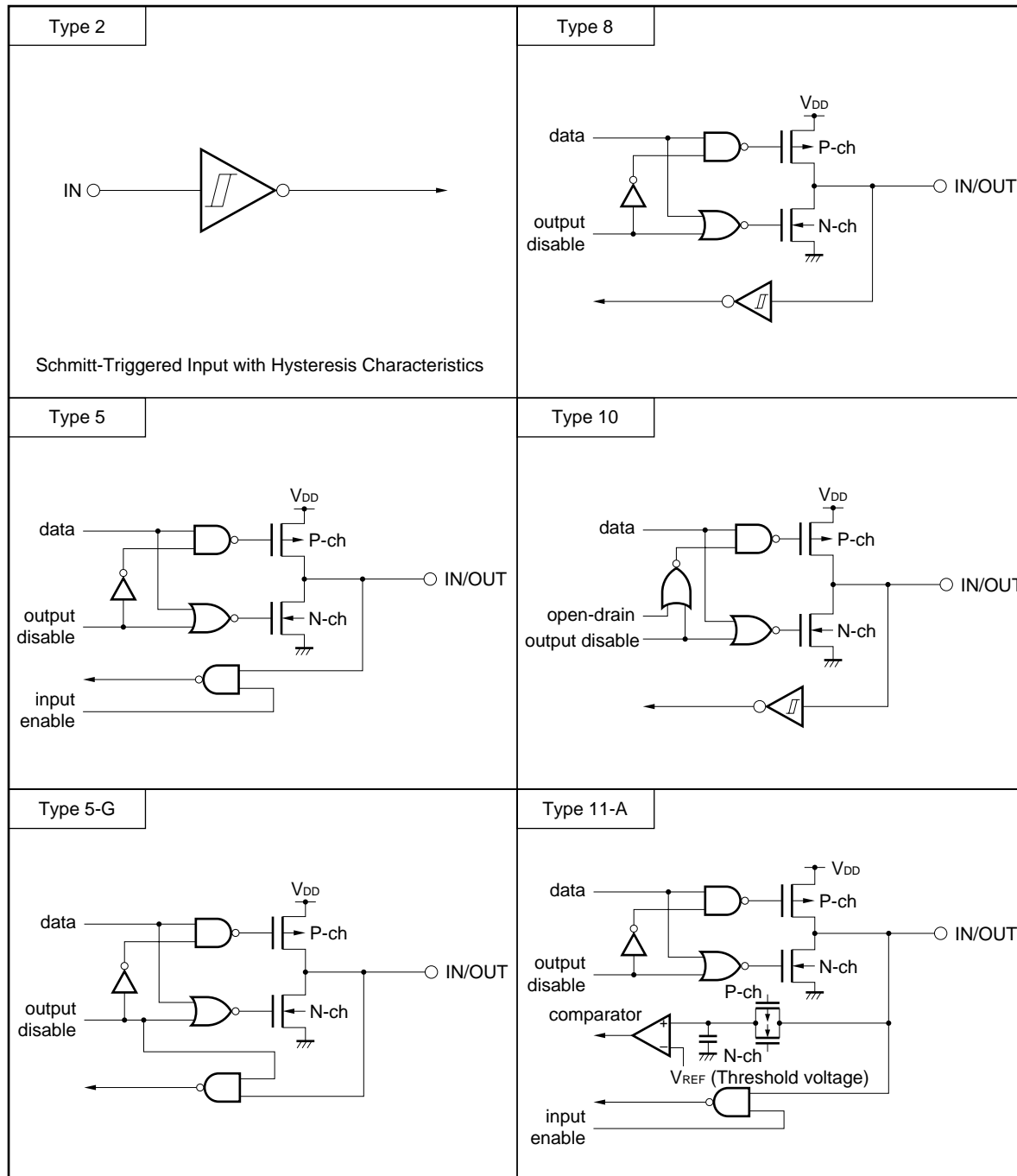
**1.3 Pins Input/Output Circuits and Recommended Connection of Unused Pins**

Table 1-1 shows the input/output circuit types of pins and the recommended conditions for unused pins. Refer to Figure 1-1 for the configuration of the input/output circuit of each type.

**Table 1-1. Type of I/O Circuit of Each Pin**

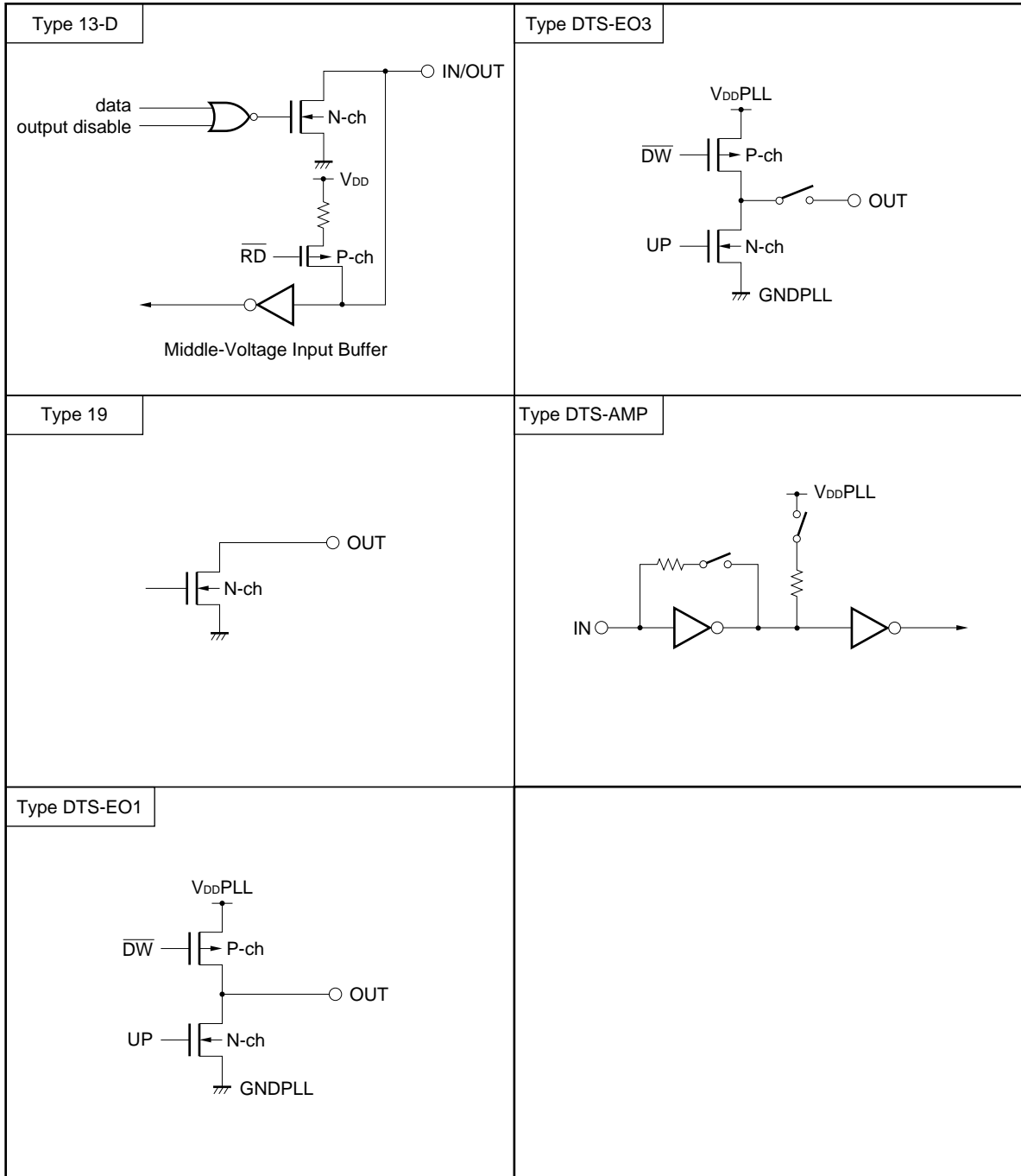
Pin Name	I/O Circuit Type	I/O	Recommended Connections of Unused Pins
P00/INTP0	2	Input	Connected to GND or GNDPORT
P01/INTP1 to P06/INTP6	8	I/O	Set in general-purpose input port mode by software and individually connected to V <sub>DD</sub> , V <sub>DD</sub> PORT, GND, or GNDPORT via a resistor.
P10/ANI0 to P15/ANI5	11-A		
P20/SI1	8		
P21/SO1	5		
P22/SCK1	8		
P23/STB	5		
P24/BUSY	8		
P25/SI0/SB0/SDA0 P26/SO0/SB1/SDA1 P27/SCK0/SCL	10		
P30 to P32	5		
P33/TI1, P34/TI2	8		
P35 P36/BEEP P37	5		
P40 to P47	5-G		
P50 to P57	5		
P60 to P63	13-D		
P64 to P67	5		
P120 to P125			
P132/PWM0 to P134/PWM2	19		
EO0	DTS-EO1	Open	
EO1	DTS-EO3		
VCOL, VCOH AMIFC, FMIFC	DTS-AMP	Input	Set to disabled status by software and open
V <sub>PP</sub>	—	—	Connected to GND or GNDPORT directly

Figure 1-1. Types of Pin Input/Output Circuits (1/2)



**Remark** All  $V_{DD}$  and GND in the above figures are the positive power supply and ground potential of the ports, and should be read as  $V_{DDPORT}$  and  $GNDPORT$ , respectively.

Figure 1-1. Types of Pin Input/Output Circuits (2/2)



**Remark** All  $V_{DD}$  and  $GND$  in the above figures are the positive power supply and ground potential of the ports, and should be read as  $V_{DDPORT}$  and  $GNDPORT$ , respectively.

**2. PROM PROGRAMMING**

The μPD178P018A has an internal 60-Kbyte PROM as a program memory. For programming, set the PROM programming mode with the V<sub>PP</sub> and  $\overline{\text{RESET}}$  pins. For the connection of unused pins, refer to “PIN CONFIGURATIONS (TOP VIEW) (2) PROM programming mode.”

**Caution** Programs must be written in addresses 0000H to EFFFH (the last address EFFFH must be specified). They cannot be written by a PROM writer which cannot specify the write address.

**2.1 Operating Modes**

When +5 V or +12.5 V is applied to the V<sub>PP</sub> pin and a low-level signal is applied to the  $\overline{\text{RESET}}$  pin, the PROM programming mode is set. This mode will become the operating mode as shown in Table 2-1 when the  $\overline{\text{CE}}$ ,  $\overline{\text{OE}}$ , and PGM pins are set as shown.

Further, when the read mode is set, it is possible to read the contents of the PROM.

**Table 2-1. Operating Modes of PROM Programming**

Pin	$\overline{\text{RESET}}$	V <sub>PP</sub>	V <sub>DD</sub>	$\overline{\text{CE}}$	$\overline{\text{OE}}$	PGM	D0 to D7
Operating Mode							
Page data latch	L	+12.5 V	+6.5 V	H	L	H	Data input
Page write				H	H	L	High-impedance
Byte write				L	H	L	Data input
Program verify				L	L	H	Data output
Program inhibit				×	H	H	High-impedance
				×	L	L	
Read		+5 V	+5 V	L	L	H	Data output
Output disable				L	H	×	High-impedance
Standby				H	×	×	High-impedance

**Remark** × : L or H



**(1) Read mode**

Read mode is set if  $\overline{CE} = L$  and  $\overline{OE} = L$  are set.

**(2) Output disable mode**

Data output becomes high-impedance, and is in the output disable mode, if  $\overline{OE} = H$  is set.

Therefore, it allows data to be read from any device by controlling the  $\overline{OE}$  pin, if multiple  $\mu$ PD178P018As are connected to the data bus.

**(3) Standby mode**

Standby mode is set if  $\overline{CE} = H$  is set.

In this mode, data outputs become high-impedance irrespective of the  $\overline{OE}$  status.

**(4) Page data latch mode**

Page data latch mode is set if  $\overline{CE} = H$ ,  $\overline{PGM} = H$ , and  $\overline{OE} = L$  are set at the beginning of page write mode.

In this mode, 1 page 4-byte data is latched in an internal address/data latch circuit.

**(5) Page write mode**

After 1 page 4 bytes of addresses and data are latched in the page data latch mode, a page write is executed by applying a 0.1-ms program pulse (active low) to the  $\overline{PGM}$  pin with  $\overline{CE} = H$  and  $\overline{OE} = H$ . Then, program verification can be performed, if  $\overline{CE} = L$  and  $\overline{OE} = L$  are set.

If programming is not performed by a one-time program pulse, X times ( $X \leq 10$ ) write and verification operations should be executed repeatedly.

**(6) Byte write mode**

Byte write is executed when a 0.1-ms program pulse (active low) is applied to the  $\overline{PGM}$  pin with  $\overline{CE} = L$  and  $\overline{OE} = H$ . Then, program verification can be performed if  $\overline{OE} = L$  is set.

If programming is not performed by a one-time program pulse, X times ( $X \leq 10$ ) write and verification operations should be executed repeatedly.

**(7) Program verify mode**

Program verify mode is set if  $\overline{CE} = L$ ,  $\overline{PGM} = H$ , and  $\overline{OE} = L$  are set.

In this mode, check if a write operation is performed correctly after the write.

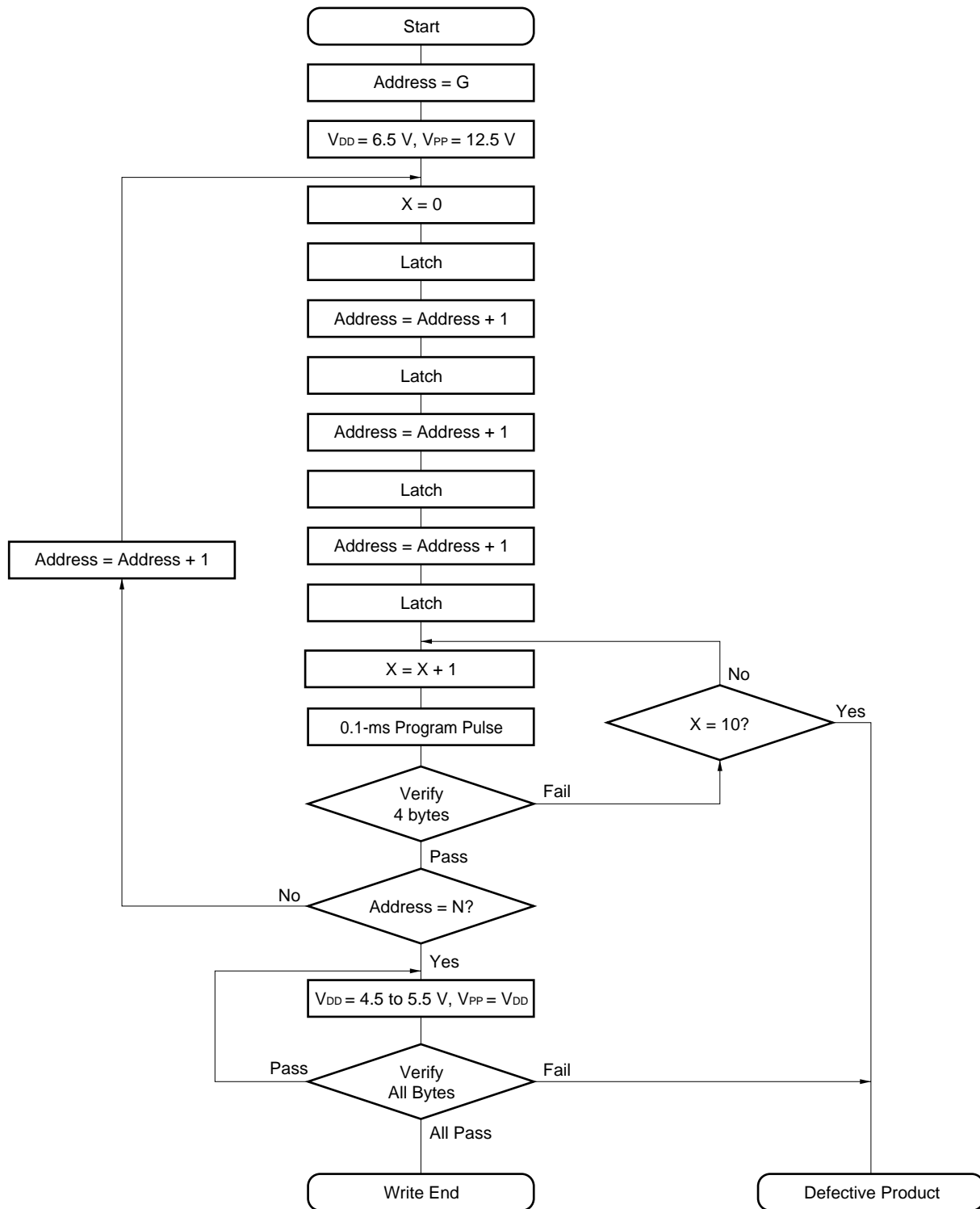
**(8) Program inhibit mode**

Program inhibit mode is used when the  $\overline{OE}$  pin,  $V_{PP}$  pin, and D0 to D7 pins of multiple  $\mu$ PD178P018As are connected in parallel and a write is performed to one of those devices.

When a write operation is performed, the page write mode or byte write mode described above is used. At this time, a write is not performed to a device which has the  $\overline{PGM}$  pin driven high.

2.2 PROM Write Procedure

Figure 2-1. Page Program Mode Flow Chart



**Remark** G = Start address  
 N = Program last address

Figure 2-2. Page Program Mode Timing

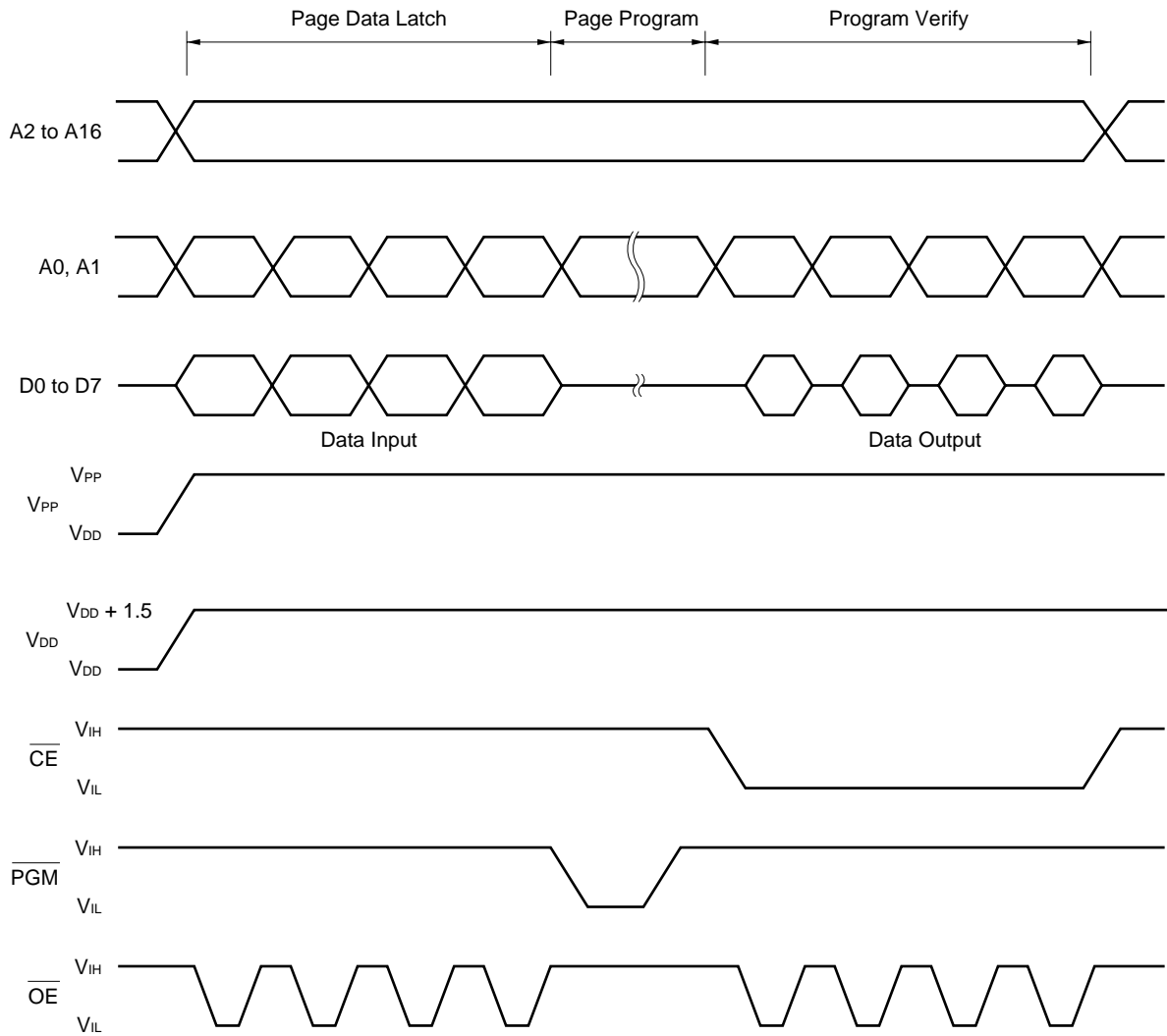
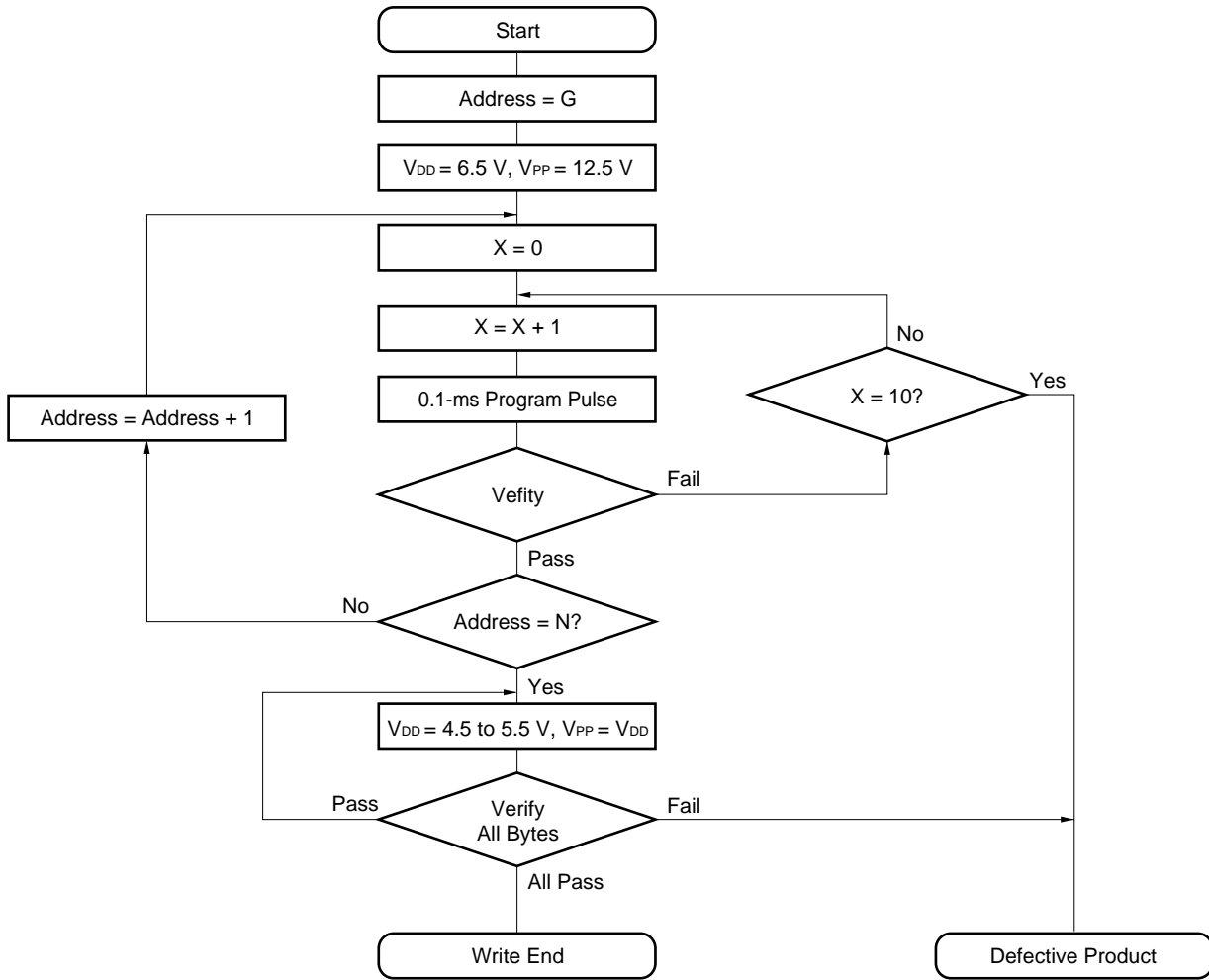
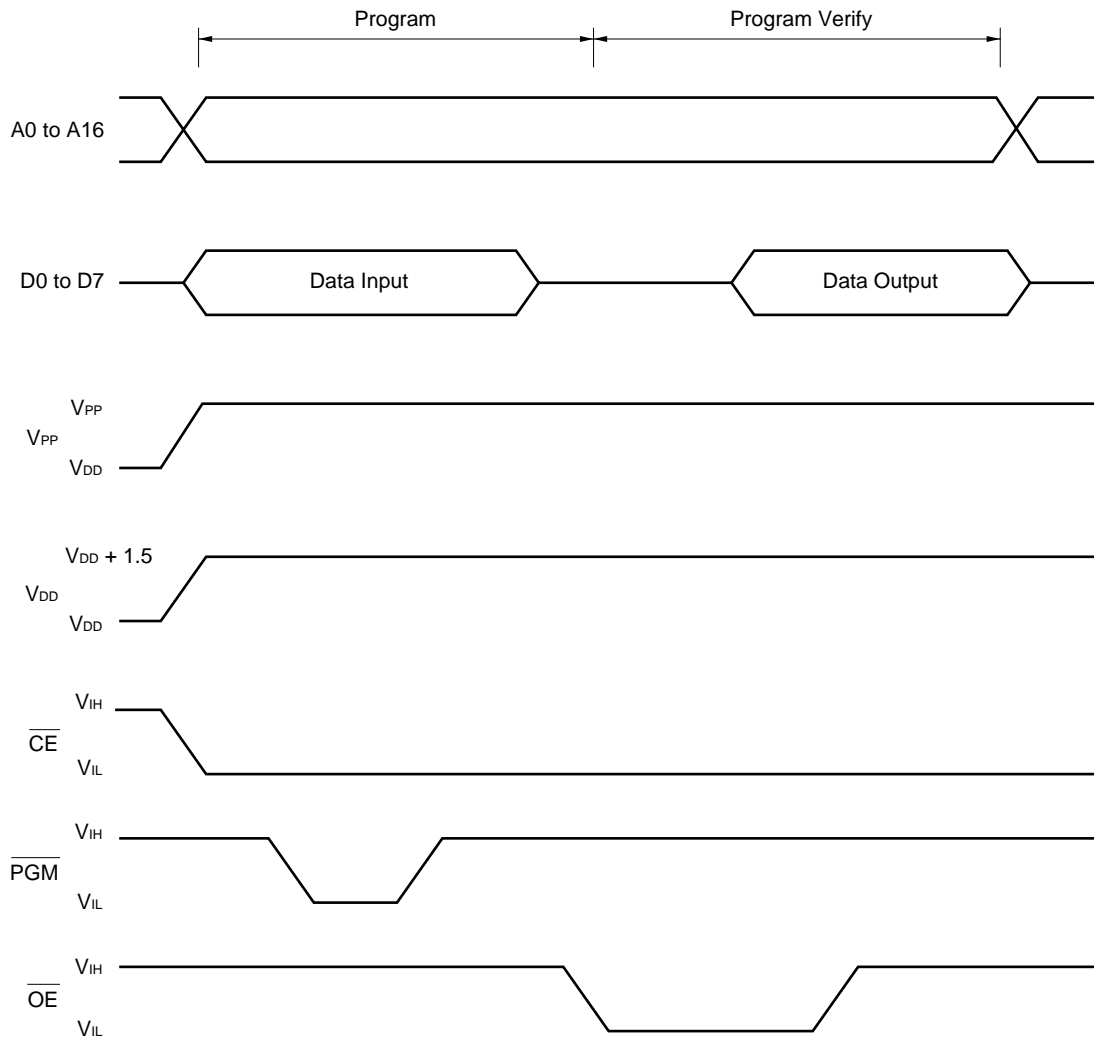


Figure 2-3. Byte Program Mode Flow Chart



**Remark** G = Start address  
 N = Program last address

Figure 2-4. Byte Program Mode Timing



- Cautions**
1. V<sub>DD</sub> should be applied before V<sub>PP</sub>, and removed after V<sub>PP</sub>.
  2. V<sub>PP</sub> must not exceed +13.5 V including overshoot.
  3. Reliability may be adversely affected if removal/reinsertion is performed while +12.5 V is being applied to V<sub>PP</sub>.

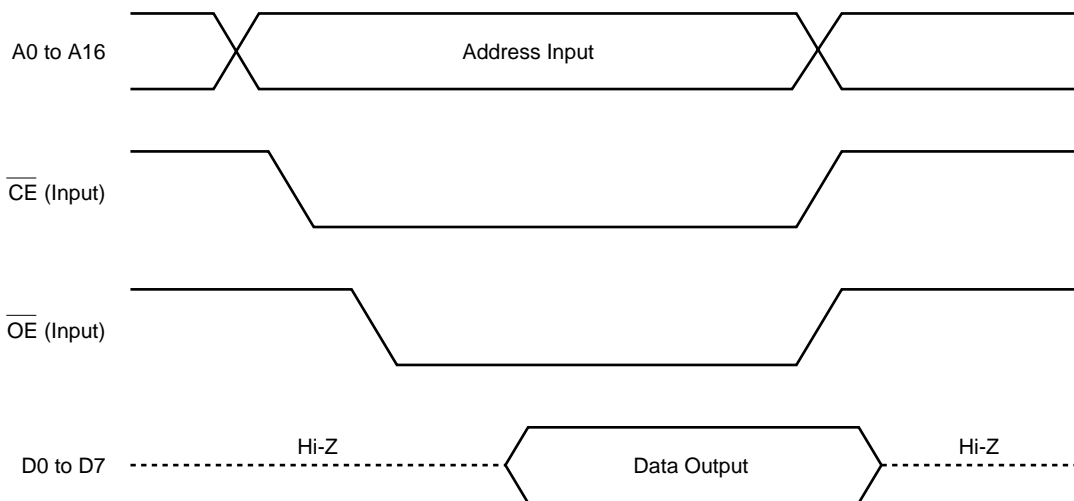
**2.3 PROM Read Procedure**

The contents of PROM are readable to the external data bus (D0 to D7) according to the read procedure shown below.

- (1) Fix the  $\overline{\text{RESET}}$  pin at low level, supply +5 V to the  $V_{PP}$  pin, and connect all other unused pins as shown in **“PIN CONFIGURATIONS (TOP VIEW) (2) PROM programming mode”**.
- (2) Supply +5 V to the  $V_{DD}$  and  $V_{PP}$  pins.
- (3) Input address of read data into the A0 to A16 pins.
- (4) Read mode
- (5) Output data to D0 to D7 pins.

The timings of the above steps (2) to (5) are shown in Figure 2-5.

**Figure 2-5. PROM Read Timings**



**3. PROGRAM ERASURE (μPD178P018AKK-T ONLY)**

The μPD178P018AKK-T is capable of erasing (FFH) the data written in a program memory and rewriting.

To erase the programmed data, expose the erasure window to light having a wavelength shorter than about 400 nm. Normally, irradiate ultraviolet rays of 254-nm wavelength. The amount of exposure required to completely erase the programmed data is as follows:

- UV intensity x erasure time: 30 W•s/cm<sup>2</sup> or more
- Erasure time: 40 min. or more (When a UV lamp of 12 000 μW/cm<sup>2</sup> is used. However, a longer time may be needed because of deterioration in performance of the UV lamp, soiled erasure window, etc.)

When erasing the contents of the data, set up the UV lamp within 2.5 cm from the erasure window. Further, if a filter is provided for a UV lamp, irradiate the ultraviolet rays after removing the filter.

**4. OPAQUE FILM ON ERASURE WINDOW (μPD178P018AKK-T ONLY)**

To protect from an intentional erasure by rays other than that of the lamp for erasing EPROM contents, or to protect internal circuit other than EPROM from misoperating by rays, cover the erasure window with an opaque film when EPROM contents erasure is not performed.

**5. ONE-TIME PROM VERSION SCREENING**

The one-time PROM version (μPD178P018AGC-3B9) cannot be tested completely by NEC before it is shipped, because of its structure. It is recommended to perform screening to verify PROM after writing necessary data and performing high-temperature storage under the condition below.

Storage Temperature	Storage Time
125 °C	24 hours

6. ELECTRICAL SPECIFICATIONS (PRELIMINARY)

**Caution** The following electrical specifications are preliminary values for this product. When designing, be sure to refer to the data sheet describing the official electrical specifications.

μPD178P018A Data Sheet: to be prepared

ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25 °C)

Parameter	Symbol	Test Conditions		Ratings	Unit
Power supply voltage	V <sub>DD</sub>			-0.3 to +7.0	V
	V <sub>PP</sub>			-0.3 to +13.5	V
Input voltage	V <sub>I1</sub>	Excluding P60 to P63		-0.3 to V <sub>DD</sub> + 0.3	V
	V <sub>I2</sub>	P60 to P63	N-ch open-drain	-0.3 to +16	V
	V <sub>I3</sub>	A9	PROM programming mode	-0.3 to +13.5	V
Output voltage	V <sub>O</sub>			-0.3 to V <sub>DD</sub> + 0.3	V
Output withstand voltage	V <sub>BDS</sub>	P132 to P134	N-ch open-drain	16	V
Analog input voltage	V <sub>AN</sub>	P10 to P15	Analog input pin	-0.3 to V <sub>DD</sub> + 0.3	V
Output current high	I <sub>OH</sub>	1 pin		-10	mA
		P01 to P06, P30 to P37, P56, P57, P60 to P67, P120 to P125 total		-15	mA
		P10 to P15, P20 to P27, P40 to P47, P50 to P55, P132 to P134 total		-15	mA
Output current low	I <sub>OL</sub> <sup>Note</sup>	1 pin	Peak value	15	mA
			r.m.s. value	7.5	mA
Operating ambient temperature	T <sub>A</sub>			-40 to +85	°C
Storage temperature	T <sub>stg</sub>			-65 to +150	°C

**Note** r.m.s. (root mean square) value should be calculated as follows: [r.m.s value] = [Peak value] × √duty

**Caution** Product quality may suffer if the absolute maximum rating is exceeded for even a single parameter even momentarily. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions which ensure that the absolute maximum ratings are not exceeded.

**Remark** The characteristics of an alternate-function pin and a port pin are the same unless specified otherwise.

RECOMMENDED SUPPLY VOLTAGE RANGES (T<sub>A</sub> = -40 to +85 °C)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage	V <sub>DD1</sub>	During CPU operation and PLL operation.	4.5		5.5	V
	V <sub>DD2</sub>	While the CPU is operating and the PLL is stopped. Cycle Time: T <sub>CY</sub> ≥ 0.89 μs	3.5		5.5	V
	V <sub>DD3</sub>	While the CPU is operating and the PLL is stopped. Cycle Time: T <sub>CY</sub> = 0.44 μs	4.5		5.5	V

**Remark** T<sub>CY</sub>: Cycle Time (Minimum instruction execution time)



DC CHARACTERISTICS (T<sub>A</sub> = -40 to +85 °C, V<sub>DD</sub> = 3.5 to 5.5 V)

(1/3)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit	
Input voltage high	V <sub>IH1</sub>	P10 to P15, P21, P23, P30 to P32, P35 to P37, P40 to P47, P50 to P57, P64 to P67, P120 to P125	0.7 V <sub>DD</sub>		V <sub>DD</sub>	V	
	V <sub>IH2</sub>	P00 to P06, P20, P22, P24 to P27, P33, P34, RESET	0.85 V <sub>DD</sub>		V <sub>DD</sub>	V	
	V <sub>IH3</sub>	P60 to P63 (N-ch open-drain)	0.7 V <sub>DD</sub>		15	V	
Input voltage low	V <sub>IL1</sub>	P10 to P15, P21, P23, P30 to P32, P35 to P37, P40 to P47, P50 to P57, P64 to P67, P120 to P125	0		0.3 V <sub>DD</sub>	V	
	V <sub>IL2</sub>	P00 to P06, P20, P22, P24 to P27, P33, P34, RESET	0		0.15 V <sub>DD</sub>	V	
	V <sub>IL3</sub>	P60 to P63 (N-ch open-drain)	4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	0		0.3 V <sub>DD</sub>	V
			3.5 V ≤ V <sub>DD</sub> < 4.5 V	0		0.2 V <sub>DD</sub>	V
Output voltage high	V <sub>OH1</sub>	4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V, I <sub>OH</sub> = -1 mA	V <sub>DD</sub> - 1.0			V	
		3.5 V ≤ V <sub>DD</sub> < 4.5 V, I <sub>OH</sub> = -100 μA	V <sub>DD</sub> - 0.5			V	
Output voltage low	V <sub>OL1</sub>	P50 to P57, P60 to P63	V <sub>DD</sub> = 4.5 to 5.5 V, I <sub>OH</sub> = 15 mA		0.4	2.0	V
		P01 to P06, P10 to P15, P20 to P27, P30 to P37, P40 to P47, P64 to P67, P120 to P125, P132 to P134	V <sub>DD</sub> = 4.5 to 5.5 V, I <sub>OL</sub> = 1.6 mA			0.4	V
	V <sub>OL2</sub>	SB0, SB1, SCK0	V <sub>DD</sub> = 4.5 to 5.5 V, N-ch open-drain pulled-up (R = 1 KΩ)			0.2 V <sub>DD</sub>	V

**Remark** The characteristics of an alternate-function pin and a port pin are the same unless specified otherwise.

DC CHARACTERISTICS (T<sub>A</sub> = -40 to +85 °C, V<sub>DD</sub> = 3.5 to 5.5 V)

(2/3)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
Input leakage current high	I <sub>LIH1</sub>	P00 to P06, P10 to P15, P20 to P27, P30 to P37, P40 to P47, P50 to P57, P64 to P67, P120 to P125, <u>RESET</u>	V <sub>IN</sub> = V <sub>DD</sub>			3	μA
	I <sub>LIH2</sub>	P60 to P63	V <sub>IN</sub> = 15 V			80	μA
Input leakage current low	I <sub>LIL1</sub>	P00 to P06, P10 to P15, P20 to P27, P30 to P37, P40 to P47, P50 to P57, P64 to P67, P120 to P125, <u>RESET</u>	V <sub>IN</sub> = 0 V			-3	μA
	I <sub>LIL2</sub>	P60 to P63				-3 <small>Note</small>	μA
Output leakage current high	I <sub>LOH</sub>	P132 to P134	V <sub>OUT</sub> = 15 V			3	μA
Output leakage current low	I <sub>LOL</sub>	P132 to P134	V <sub>OUT</sub> = 0 V			-3	μA
Output off leak current	I <sub>LOF</sub>	EO0, EO1	V <sub>OUT</sub> = V <sub>DD</sub> , V <sub>OUT</sub> = 0 V			±1	μA

**Note** When an input instruction is executed, the low-level input leakage current for P60 to P63 becomes -200 μA (MAX.) only in one clock cycle (at no wait). It remains at -3 μA (MAX.) for other than an input instruction.

**Remark** The characteristics of an alternate-function pin and a port pin are the same unless specified otherwise.

REFERENCE CHARACTERISTICS (T<sub>A</sub> = 25 °C, V<sub>DD</sub> = 5 V)

(1/2)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
Output current high	I <sub>OH1</sub>	EO0	V <sub>OUT</sub> = V <sub>DD</sub> - 1 V		-4		mA
		EO1 (EOCON0 = 0)		-1.8			mA
Output current low	I <sub>OL1</sub>	EO0	V <sub>OUT</sub> = 1 V		6		mA
		EO1 (EOCON0 = 0)		3.5			mA

DC CHARACTERISTICS (T<sub>A</sub> = -40 to +85 °C, V<sub>DD</sub> = 3.5 to 5.5 V)

(3/3)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
Power supply current <sup>Note 1</sup>	I <sub>DD1</sub>	While the CPU is operating and the PLL is stopped	T <sub>CY</sub> = 0.89 μs <sup>Note 2</sup>		2.5	15	mA
	I <sub>DD2</sub>	f <sub>X</sub> = 4.5-MHz operation	T <sub>CY</sub> = 0.44 μs <sup>Note 3</sup> V <sub>DD</sub> = 4.5 to 5.5 V		4.0	27	mA
	I <sub>DD3</sub>	While the CPU is operating and the PLL is stopped HALT Mode.	T <sub>CY</sub> = 0.89 μs <sup>Note 2</sup>		1	4	mA
	I <sub>DD4</sub>	Pin X1 sine wave input V <sub>IN</sub> = V <sub>DD</sub> f <sub>X</sub> = 4.5-MHz operation	T <sub>CY</sub> = 0.44 μs <sup>Note 3</sup> V <sub>DD</sub> = 4.5 to 5.5 V		1.6	6	mA
Data hold power supply voltage	V <sub>DDR1</sub>	When the crystal is oscillating	T <sub>CY</sub> = 0.44 μs	4.5		5.5	V
	V <sub>DDR2</sub>		T <sub>CY</sub> = 0.89 μs	3.5		5.5	V
	V <sub>DDR3</sub>	When the crystal oscillation is stopped When power off by Power On Clear is detected		2.7		5.5	V
Data hold power supply current	I <sub>DDR1</sub>	While the crystal oscillation is stopped	T <sub>A</sub> = 25 °C, V <sub>DD</sub> = 5 V		2	4	μA
	I <sub>DDR2</sub>				2	30	μA

**Notes** 1. The port current is not included.

2. When the Processor Clock Control register (PCC) is set at 00H, and the Oscillation Mode Select register (OSMS) is set to 00H.

3. When PCC is set to 00H and OSMS is set to 01H.

**Remarks** 1. T<sub>CY</sub>: Cycle Time (Minimum instruction execution time)

2. f<sub>X</sub>: System clock oscillation frequency.

REFERENCE CHARACTERISTICS (T<sub>A</sub> = 25 °C, V<sub>DD</sub> = 5 V)

(2/2)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
Power supply current	I <sub>DD5</sub>	During CPU operation and PLL operation. VCOH pin sine wave input f <sub>IN</sub> = 130 MHz, V <sub>IN</sub> = 0.15 V <sub>P-P</sub>	T <sub>CY</sub> = 0.44 μs <sup>Note</sup>		7		mA

**Note** When the Processor Clock Control register (PCC) is set to 00H, and the Oscillation Mode Select register (OSMS) is set to 01H.

**Remark** T<sub>CY</sub>: Cycle Time (Minimum instruction execution time)

AC CHARACTERISTICS

(1) BASIC OPERATION (T<sub>A</sub> = -40 to +85 °C, V<sub>DD</sub> = 3.5 to 5.5 V)

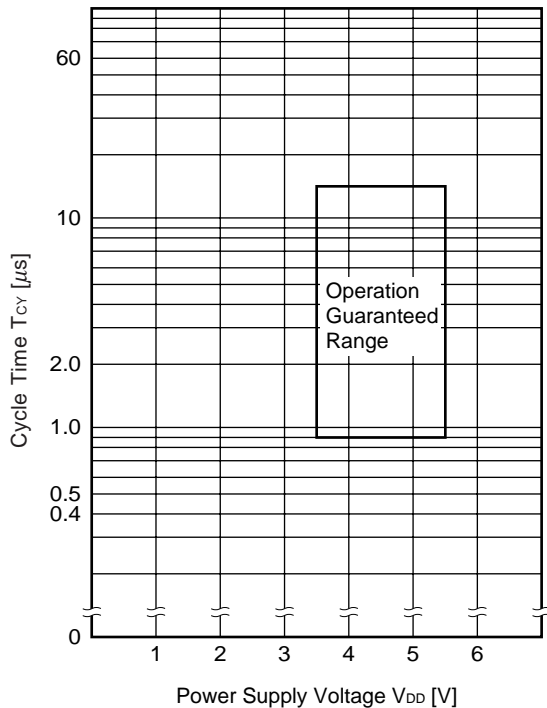
Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Cycle time (Minimum instruction execution time)	T <sub>CY</sub>	f <sub>XX</sub> = f <sub>X</sub> /2 <sup>Note 1</sup> , f <sub>X</sub> = 4.5-MHz operation	0.89		14.22	μs
		f <sub>XX</sub> = f <sub>X</sub> <sup>Note 2</sup> , f <sub>X</sub> = 4.5-MHz operation	4.5 ≤ V <sub>DD</sub> ≤ 5.5 V	0.44	7.11	μs
			3.5 ≤ V <sub>DD</sub> < 4.5 V	0.89	7.11	μs
TI1, TI2 input frequency	f <sub>TI</sub>	4.5 ≤ V <sub>DD</sub> ≤ 5.5 V	0		4.5	MHz
		3.5 V ≤ V <sub>DD</sub> < 4.5 V	0		275	kHz
TI1, TI2 input high/ low-level width	t <sub>TIH</sub> , t <sub>TIL</sub>	4.5 ≤ V <sub>DD</sub> ≤ 5.5 V	111			ns
		3.5 V ≤ V <sub>DD</sub> < 4.5 V	1.8			μs
Interrupt input high/ low-level width	T <sub>INTH</sub> , T <sub>INTL</sub>	INTP0	8/f <sub>sam</sub> <sup>Note 3</sup>			μs
		INTP1 to INTP6	10			μs
RESET low-level width	t <sub>RSL</sub>		10			μs

- Notes**
1. When the Oscillation Mode Selection register (OSMS) is set to 00H.
  2. When OSMS is set to 01H.
  3. In combination with bits 0 (SCS0) and 1 (SCS1) of the Sampling Clock Select register (SCS), selection of f<sub>sam</sub> is possible among f<sub>XX</sub>/2<sup>N</sup>, f<sub>XX</sub>/32, f<sub>XX</sub>/64, and f<sub>XX</sub>/128 (when N = 0 to 4).

- Remarks**
1. f<sub>XX</sub>: System clock frequency (f<sub>X</sub> or f<sub>X</sub>/2)
  2. f<sub>X</sub>: System clock oscillation frequency

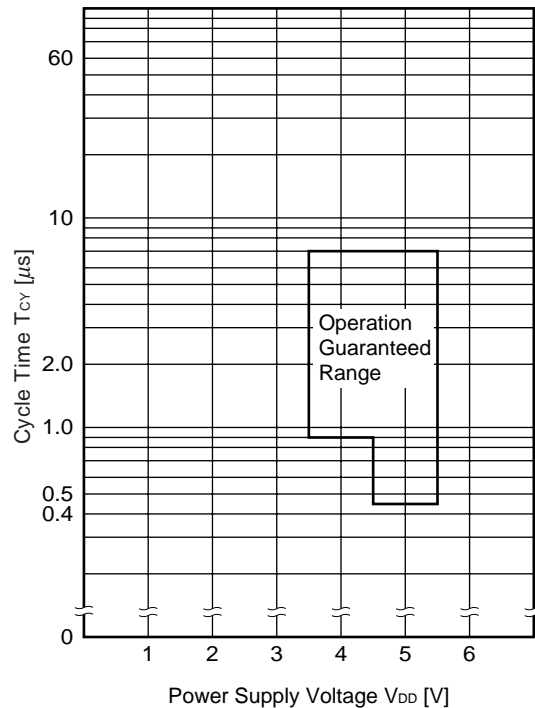
T<sub>CY</sub> vs V<sub>DD</sub>

(when system clock f<sub>XX</sub> is operating at f<sub>X</sub>/2)



T<sub>CY</sub> vs V<sub>DD</sub>

(when system clock f<sub>XX</sub> is operating at f<sub>X</sub>)



(2) SERIAL INTERFACE (T<sub>A</sub> = -40 to +85 °C, V<sub>DD</sub> = 3.5 to 5.5 V)

(a) Serial interface channel 0

(i) 3-wire serial I/O mode ( $\overline{\text{SCK0}}$  ... internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK0}}$ cycle time	t <sub>KCY1</sub>	4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	800			ns
		3.5 V ≤ V <sub>DD</sub> < 4.5 V	1 600			ns
$\overline{\text{SCK0}}$ high-/low-level width	t <sub>KH1</sub> ,	4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	t <sub>KCY1</sub> /2 - 50			ns
	t <sub>KL1</sub>	3.5 V ≤ V <sub>DD</sub> < 4.5 V	t <sub>KCY1</sub> /2 - 100			ns
SI0 setup time (to $\overline{\text{SCK0}}\uparrow$ )	t <sub>SIK1</sub>	4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	100			ns
		3.5 V ≤ V <sub>DD</sub> < 4.5 V	150			ns
SI0 hold time (from $\overline{\text{SCK0}}\uparrow$ )	t <sub>KSI1</sub>		400			ns
SO0 output delay time from $\overline{\text{SCK0}}\downarrow$	t <sub>KSO1</sub>	C = 100 pF <sup>Note</sup>			300	ns

**Note** C is the load capacitance of the SO0 output line.

(ii) 3-wire serial I/O mode ( $\overline{\text{SCK0}}$  ... external clock input)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK0}}$ cycle time	t <sub>KCY2</sub>	4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	800			ns
		3.5 V ≤ V <sub>DD</sub> < 4.5 V	1 600			ns
$\overline{\text{SCK0}}$ high-/low-level width	t <sub>KH2</sub> ,	4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	400			ns
	t <sub>KL2</sub>	3.5 V ≤ V <sub>DD</sub> < 4.5 V	800			ns
SI0 setup time (to $\overline{\text{SCK0}}\uparrow$ )	t <sub>SIK2</sub>		100			ns
SI0 hold time (from $\overline{\text{SCK0}}\uparrow$ )	t <sub>KSI2</sub>		400			ns
SO0 output delay time from $\overline{\text{SCK0}}\downarrow$	t <sub>KSO2</sub>	C = 100 pF <sup>Note</sup>			300	ns
$\overline{\text{SCK0}}$ rising or falling edge time	t <sub>R2</sub> , t <sub>F2</sub>				1 000	ns

**Note** C is the load capacitance of the SO0 output line.

(iii) SBI mode ( $\overline{\text{SCK0}}$  ... internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK0}}$ cycle time	$t_{\text{KCY3}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	800			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	3 200			ns
$\overline{\text{SCK0}}$ high-/low-level width	$t_{\text{KH3}}$ ,	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	$t_{\text{KCY3}}/2 - 50$			ns
	$t_{\text{KL3}}$	$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	$t_{\text{KCY3}}/2 - 150$			ns
SB0, SB1 setup time (to $\overline{\text{SCK0}}\uparrow$ )	$t_{\text{SIK3}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	100			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	300			ns
SB0, SB1 hold time (from $\overline{\text{SCK0}}\uparrow$ )	$t_{\text{KSI3}}$		$t_{\text{KCY3}}/2$			ns
SB0, SB1 output delay time from $\overline{\text{SCK0}}\downarrow$	$t_{\text{KSO3}}$	$R = 1 \text{ k}\Omega$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	0	250	ns
		$C = 100 \text{ pF}^{\text{Note}}$	$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	0	1 000	ns
SB0, SB1 $\downarrow$ from $\overline{\text{SCK0}}\uparrow$	$t_{\text{KSB}}$		$t_{\text{KCY3}}$			ns
$\overline{\text{SCK0}}\downarrow$ from SB0, SB1 $\downarrow$	$t_{\text{SBK}}$		$t_{\text{KCY3}}$			ns
SB0, SB1 high-level width	$t_{\text{SBH}}$		$t_{\text{KCY3}}$			ns
SB0, SB1 low-level width	$t_{\text{SBL}}$		$t_{\text{KCY3}}$			ns

**Note** R and C are the load resistance and load capacitance of the SB0 and SB1 output lines.

(iv) SBI mode ( $\overline{\text{SCK0}}$  ... external clock input)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK0}}$ cycle time	$t_{\text{KCY4}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	800			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	3 200			ns
$\overline{\text{SCK0}}$ high-/low-level width	$t_{\text{KH4}}$ ,	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	400			ns
	$t_{\text{KL4}}$	$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	1 600			ns
SB0, SB1 setup time (to $\overline{\text{SCK0}}\uparrow$ )	$t_{\text{SIK4}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	100			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	300			ns
SB0, SB1 hold time (from $\overline{\text{SCK0}}\uparrow$ )	$t_{\text{KSI4}}$		$t_{\text{KCY4}}/2$			ns
SB0, SB1 output delay time from $\overline{\text{SCK0}}\downarrow$	$t_{\text{KSO4}}$	$R = 1 \text{ k}\Omega$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	0	300	ns
		$C = 100 \text{ pF}^{\text{Note}}$	$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	0	1 000	ns
SB0, SB1 $\downarrow$ from $\overline{\text{SCK0}}\uparrow$	$t_{\text{KSB}}$		$t_{\text{KCY4}}$			ns
$\overline{\text{SCK0}}\downarrow$ from SB0, SB1 $\downarrow$	$t_{\text{SBK}}$		$t_{\text{KCY4}}$			ns
SB0, SB1 high-level width	$t_{\text{SBH}}$		$t_{\text{KCY4}}$			ns
SB0, SB1 low-level width	$t_{\text{SBL}}$		$t_{\text{KCY4}}$			ns
$\overline{\text{SCK0}}$ rising or falling edge time	$t_{\text{R4}}, t_{\text{F4}}$				1 000	ns

**Note** R and C are the load resistance and load capacitance of the SB0 and SB1 output lines.

(v) 2-wire serial I/O mode ( $\overline{\text{SCK0}}$  ... internal clock output)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK0}}$ cycle time	$t_{\text{KCY5}}$	R = 1 kΩ C = 100 pF <sup>Note</sup>		1 600			ns
$\overline{\text{SCK0}}$ high-level width	$t_{\text{KH5}}$			$t_{\text{KCY5}}/2 - 160$			ns
$\overline{\text{SCK0}}$ low-level width	$t_{\text{KL5}}$		4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	$t_{\text{KCY5}}/2 - 50$			ns
			3.5 V ≤ V <sub>DD</sub> < 4.5 V	$t_{\text{KCY5}}/2 - 100$			ns
SB0, SB1 setup time (to $\overline{\text{SCK0}}\uparrow$ )	$t_{\text{SIK5}}$		4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	300			ns
			3.5 V ≤ V <sub>DD</sub> < 4.5 V	350			ns
				400			ns
SB0, SB1 hold time (from $\overline{\text{SCK0}}\uparrow$ )	$t_{\text{KSI5}}$			600			ns
SB0, SB1 output delay time from $\overline{\text{SCK0}}\downarrow$	$t_{\text{KSO5}}$		0		300	ns	

**Note** R and C are the load resistance and load capacitance of the  $\overline{\text{SCK0}}$ , SB0, and SB1 output lines.

(vi) 2-wire serial I/O mode ( $\overline{\text{SCK0}}$  ... external clock input)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK0}}$ cycle time	$t_{\text{KCY6}}$			1 600			ns
$\overline{\text{SCK0}}$ high-level width	$t_{\text{KH6}}$			650			ns
$\overline{\text{SCK0}}$ low-level width	$t_{\text{KL6}}$			800			ns
SB0, SB1 setup time (to $\overline{\text{SCK0}}\uparrow$ )	$t_{\text{SIK6}}$			100			ns
SB0, SB1 hold time (from $\overline{\text{SCK0}}\uparrow$ )	$t_{\text{KSI6}}$			$t_{\text{KCY6}}/2$			ns
SB0, SB1 output delay time from $\overline{\text{SCK0}}\downarrow$	$t_{\text{KSO6}}$	R = 1 kΩ	4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	0		300	ns
		C = 100 pF <sup>Note</sup>	3.5 V ≤ V <sub>DD</sub> < 4.5 V	0		500	ns
$\overline{\text{SCK0}}$ at rising or falling edge time	$t_{\text{R6}}, t_{\text{F6}}$					1 000	ns

**Note** R and C are the load resistance and load capacitance of the SB0 and SB1 output lines.

(vii) I<sup>2</sup>C bus mode (SCL ... internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit	
SCL cycle time	t <sub>KCY7</sub>	R = 1 kΩ C = 100 pF <sup>Note</sup>	10			μs	
SCL high-level width	t <sub>KH7</sub>		t <sub>KCY7</sub> - 160			ns	
SCL low-level width	t <sub>KL7</sub>		t <sub>KCY7</sub> - 50			ns	
SDA0, SDA1 setup time (to SCL↑)	t <sub>SIK7</sub>		200			ns	
SDA0, SDA1 hold time (from SCL↓)	t <sub>KSI7</sub>		0			ns	
SDA0, SDA1 output delay time (from SCL↓)	t <sub>KSO7</sub>		4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	0		300	ns
			3.5 V ≤ V <sub>DD</sub> < 4.5 V	0		500	ns
SDA0, SDA1↓ from SCL↑ or SDA0, SDA1↑ from SCL↑	t <sub>KSB</sub>		200			ns	
SCL↓ from SDA0, SDA1↓	t <sub>SBK</sub>		400			ns	
SDA0, SDA1 high-level width	t <sub>SBH</sub>		500			ns	

**Note** R and C are the load resistance and load capacitance of the SCL, SDA0, and SDA1 output lines.

(viii) I<sup>2</sup>C bus mode (SCL ... external clock input)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit	
SCL cycle time	t <sub>KCY8</sub>		1 000			ns	
SCL high-/low-level width	t <sub>KH8</sub> , t <sub>KL8</sub>		400			ns	
SDA0, SDA1 setup time (to SCL↑)	t <sub>SIK8</sub>		200			ns	
SDA0, SDA1 hold time (from SCL↓)	t <sub>KSI8</sub>		0			ns	
SDA0, SDA1 output delay time from SCL↓	t <sub>KSO8</sub>	R = 1 kΩ C = 100 pF <sup>Note</sup>	4.5 V ≤ V <sub>DD</sub> ≤ 5.5 V	0		300	ns
			3.5 V ≤ V <sub>DD</sub> < 4.5 V	0		500	ns
SDA0, SDA1↓ from SCL↑ or SDA0, SDA1↑ from SCL↑	t <sub>KSB</sub>		200			ns	
SCL↓ from SDA0, SDA1↓	t <sub>SBK</sub>		400			ns	
SDA0, SDA1 high-level width	t <sub>SBH</sub>		500			ns	
SCL rising or falling edge time	t <sub>R8</sub> , t <sub>F8</sub>				1 000	ns	

**Note** R and C are the load resistance and load capacitance of the SDA0 and SDA1 output lines.



(b) Serial interface channel 1

(i) 3-wire serial I/O mode ( $\overline{\text{SCK1}}$  ... internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK1}}$ cycle time	$t_{\text{KCY9}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	800			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	1 600			ns
$\overline{\text{SCK1}}$ high-/low-level width	$t_{\text{KH9}}$ ,	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	$t_{\text{KCY9}}/2 - 50$			ns
	$t_{\text{KL9}}$	$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	$t_{\text{KCY9}}/2 - 100$			ns
SI1 setup time (to $\overline{\text{SCK1}}\uparrow$ )	$t_{\text{SIK9}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	100			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	150			ns
SI1 hold time (from $\overline{\text{SCK1}}\uparrow$ )	$t_{\text{KSI9}}$		400			ns
SO1 output delay time (from $\overline{\text{SCK1}}\downarrow$ )	$t_{\text{KSO9}}$	$C = 100 \text{ pF}$ <sup>Note</sup>			300	ns

**Note** C is the load capacitance of the SO1 output line.

(ii) 3-wire serial I/O mode ( $\overline{\text{SCK1}}$  ... external clock input)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK1}}$ cycle time	$t_{\text{KCY10}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	800			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	1 600			ns
$\overline{\text{SCK1}}$ high-/low-level width	$t_{\text{KH10}}$ ,	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	400			ns
	$t_{\text{KL10}}$	$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	800			ns
SI1 setup time (to $\overline{\text{SCK1}}\uparrow$ )	$t_{\text{SIK10}}$		100			ns
SI1 hold time (from $\overline{\text{SCK1}}\uparrow$ )	$t_{\text{KSI10}}$		400			ns
SO1 output delay time (from $\overline{\text{SCK1}}\downarrow$ )	$t_{\text{KSO10}}$	$C = 100 \text{ pF}$ <sup>Note</sup>			300	ns
$\overline{\text{SCK1}}$ rising or falling edge time	$t_{\text{R10}}, t_{\text{F10}}$				1 000	ns

**Note** C is the load capacitance of the SO1 output line.

(iii) 3-wire serial I/O mode with automatic transmit/receive function ( $\overline{\text{SCK1}}$  ... internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK1}}$ cycle time	$t_{\text{KCY11}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	800			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	1 600			ns
$\overline{\text{SCK1}}$ high-/low-level width	$t_{\text{KH11}},$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	$t_{\text{KCY11}}/2 - 50$			ns
	$t_{\text{KL11}}$	$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	$t_{\text{KCY11}}/2 - 100$			ns
SI1 setup time (to $\overline{\text{SCK1}}\uparrow$ )	$t_{\text{SIK11}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	100			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	150			ns
SI1 hold time (from $\overline{\text{SCK1}}\uparrow$ )	$t_{\text{KSI11}}$		400			ns
SO1 output delay time (from $\overline{\text{SCK1}}\downarrow$ )	$t_{\text{KSO11}}$	$C = 100 \text{ pF}$ <sup>Note</sup>			300	ns
STB $\uparrow$ from $\overline{\text{SCK1}}\uparrow$	$t_{\text{SBD}}$		$t_{\text{KCY11}}/2 - 100$		$t_{\text{KCY11}}/2 + 100$	ns
Strobe signal high-level width	$t_{\text{SBW}}$		$t_{\text{KCY11}} - 30$		$t_{\text{KCY11}} + 30$	ns
Busy signal setup time (to busy signal detection timing)	$t_{\text{BYS}}$		100			ns
Busy signal hold time (from busy signal detection timing)	$t_{\text{BYH}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	100			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	150			ns
$\overline{\text{SCK1}}\downarrow$ from busy inactive	$t_{\text{SPS}}$				$2t_{\text{KCY11}}$	ns

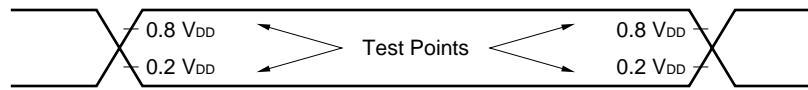
**Note** C is the load capacitance of the SO1 output line.

(iv) 3-wire serial I/O mode with automatic transmit/receive function ( $\overline{\text{SCK1}}$  ... external clock input)

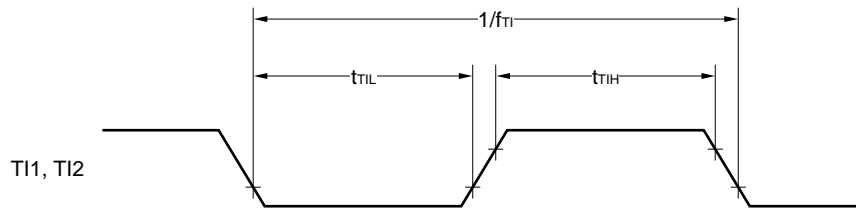
Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK1}}$ cycle time	$t_{\text{KCY12}}$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	800			ns
		$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	1 600			ns
$\overline{\text{SCK1}}$ high-/low-level width	$t_{\text{KH12}},$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	400			ns
	$t_{\text{KL12}}$	$3.5 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	800			ns
SI1 setup time (to $\overline{\text{SCK1}}\uparrow$ )	$t_{\text{SIK12}}$		100			ns
SI1 hold time (from $\overline{\text{SCK1}}\uparrow$ )	$t_{\text{KSI12}}$		400			ns
SO1 output delay time (from $\overline{\text{SCK1}}\downarrow$ )	$t_{\text{KSO12}}$	$C = 100 \text{ pF}$ <sup>Note</sup>			300	ns
$\overline{\text{SCK1}}$ rising or falling edge time	$t_{\text{R12}}, t_{\text{F12}}$				1 000	ns

**Note** C is the load capacitance of the SO1 output line.

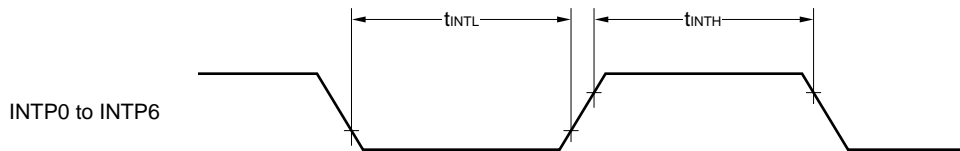
AC Timing Test Point (Excluding X1 Input)



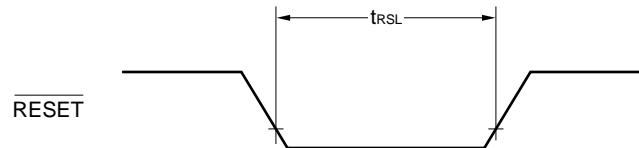
TI Timing



Interrupt Input Timing

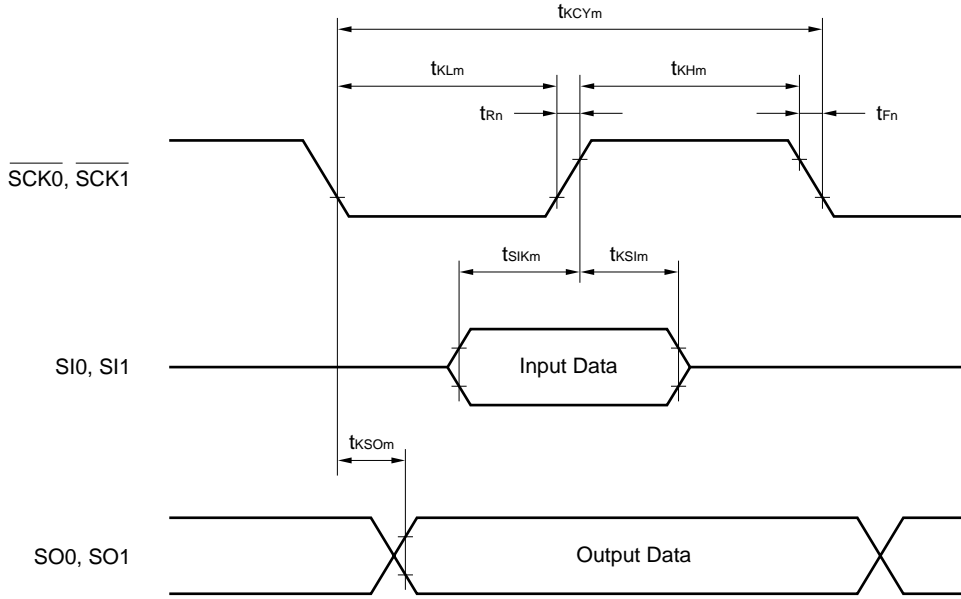


$\overline{\text{RESET}}$  Input Timing



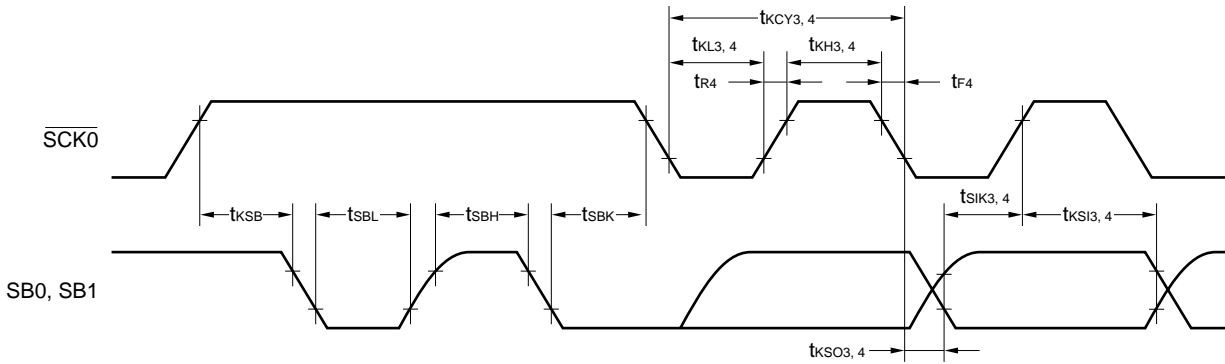
Serial Transfer Timing

3-Wire Serial I/O Mode:

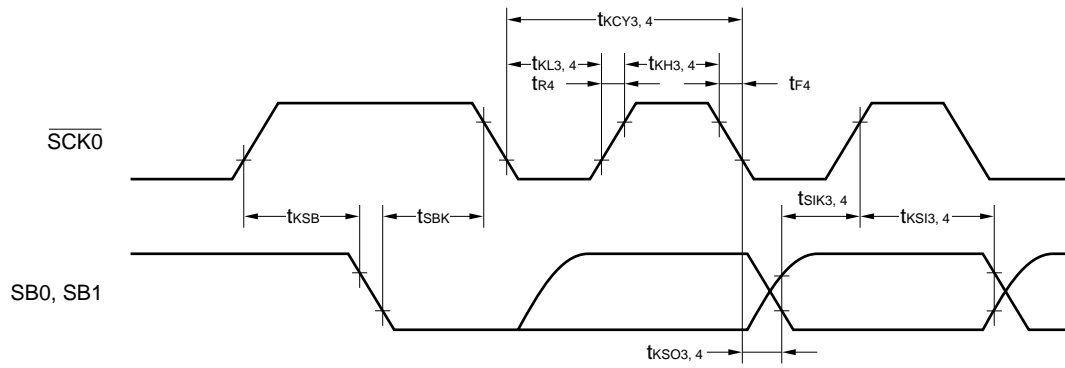


Remark  $m = 1, 2, 9, 10$   
 $n = 2, 10$

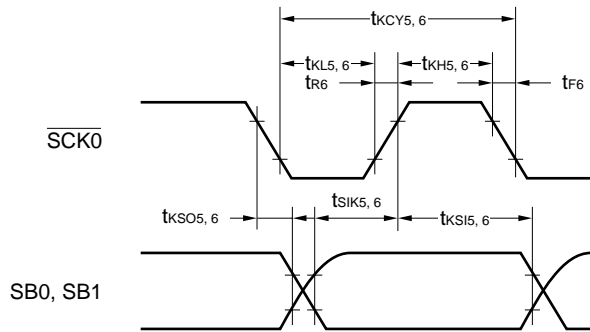
SBI Mode (Bus Release Signal Transfer):



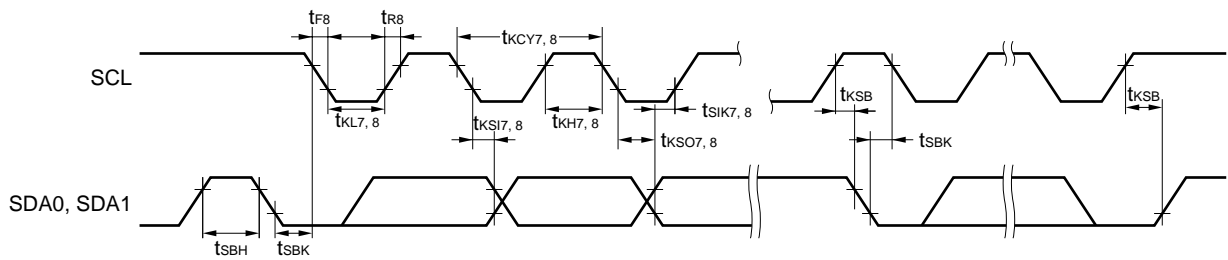
**SBI Mode (Command Signal Transfer):**



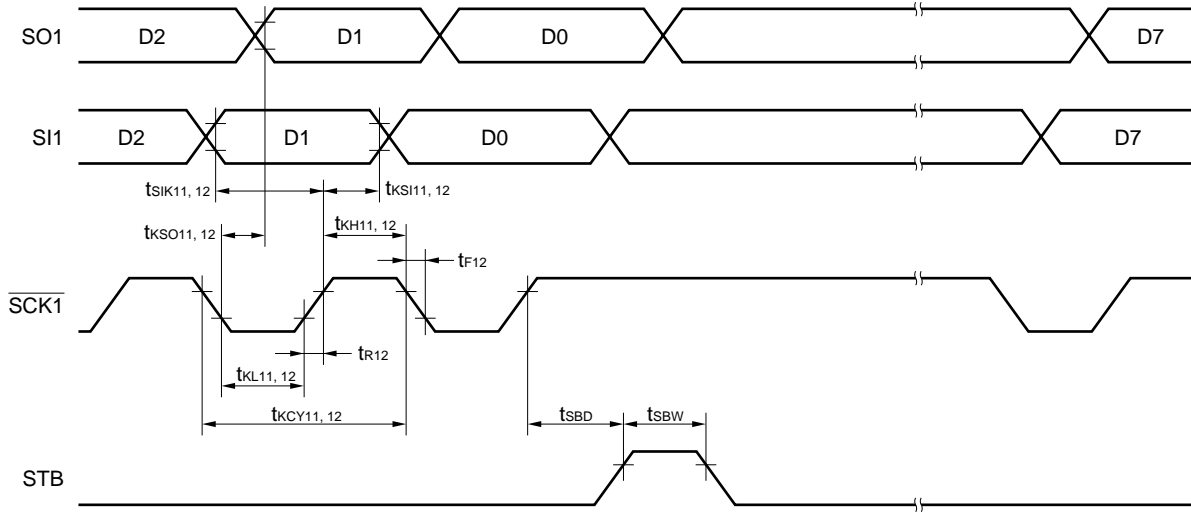
**2-Wire Serial I/O Mode:**



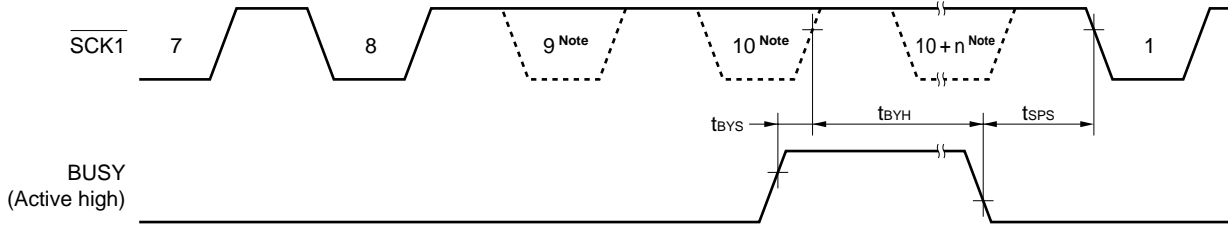
**I<sup>2</sup>C Bus Mode:**



**3-Wire Serial I/O Mode with Automatic Transmit/Receive Function:**



**3-Wire Serial I/O Mode with Automatic Transmit/Receive Function (Busy Processing):**



**Note** The signal is not actually driven low here; it is shown as such to indicate the timing.

**A/D CONVERTER CHARACTERISTICS (T<sub>A</sub> = -40 to +85 °C, V<sub>DD</sub> = 4.5 to 5.5 V)**

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Resolution			8	8	8	bit
Conversion total error					±3.0	LSB
Conversion time	t <sub>CONV</sub>		22.2		44.4	μs
Sampling time	t <sub>SAMP</sub>		15/f <sub>XX</sub>			μs
Analog input voltage	V <sub>IAN</sub>		0		V <sub>DD</sub>	V

- Remarks**
1. f<sub>XX</sub>: System clock frequency (f<sub>X</sub>/2)
  2. f<sub>X</sub>: System clock oscillation frequency

**PLL CHARACTERISTICS (T<sub>A</sub> = -40 to +85 °C, V<sub>DD</sub> = 4.5 to 5.5 V)**

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Operating frequency	f <sub>IN1</sub>	VCOL Pin MF Mode Sine wave input V <sub>IN</sub> = 0.1 V <sub>p-p</sub>	0.5		3	MHz
	f <sub>IN2</sub>	VCOL Pin HF Mode Sine wave input V <sub>IN</sub> = 0.2 V <sub>p-p</sub>	9		55	MHz
	f <sub>IN3</sub>	VCOH Pin VHF Mode Sine wave input V <sub>IN</sub> = 0.15 V <sub>p-p</sub>	60		160	MHz

**IFC CHARACTERISTICS (T<sub>A</sub> = -40 to +85 °C, V<sub>DD</sub> = 4.5 to 5.5 V)**

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Operating frequency	f <sub>IN4</sub>	AMIFC Pin AMIF Count Mode Sine wave input V <sub>IN</sub> = 0.1 V <sub>p-p</sub> <sup>Note</sup>	0.4		0.5	MHz
	f <sub>IN5</sub>	FMIFC Pin FMIF Count Mode Sine wave input V <sub>IN</sub> = 0.1 V <sub>p-p</sub> <sup>Note</sup>	10		11	MHz
	f <sub>IN6</sub>	FMIFC Pin AMIF Count Mode Sine wave input V <sub>IN</sub> = 0.1 V <sub>p-p</sub> <sup>Note</sup>	0.4		0.5	MHz

**Note** The condition of a sine wave input of V<sub>IN</sub> = 0.1 V<sub>p-p</sub> is the standard value for operation of this device during stand-alone operation, so in consideration of the effect of noise, it is recommended that operation be at an input amplitude condition of V<sub>IN</sub> = 0.15 V<sub>p-p</sub>.

PROM PROGRAMMING CHARACTERISTICS

DC CHARACTERISTICS

(1) PROM Write Mode ( $T_A = 25 \pm 5 \text{ }^\circ\text{C}$ ,  $V_{DD} = 6.5 \pm 0.25 \text{ V}$ ,  $V_{PP} = 12.5 \pm 0.3 \text{ V}$ )

Parameter	Symbol	Symbol <sup>Note</sup>	Test Conditions	MIN.	TYP.	MAX.	Unit
Input voltage, high	$V_{IH}$	$V_{IH}$		$0.7 V_{DD}$		$V_{DD}$	V
Input voltage, low	$V_{IL}$	$V_{IL}$		0		$0.3 V_{DD}$	V
Output voltage, high	$V_{OH}$	$V_{OH}$	$I_{OH} = -1 \text{ mA}$	$V_{DD} - 1.0$			V
Output voltage, low	$V_{OL}$	$V_{OL}$	$I_{OL} = 1.6 \text{ mA}$			0.4	V
Input leakage current	$I_{LI}$	$I_{LI}$	$0 \leq V_{IN} \leq V_{DD}$	-10		+10	μA
$V_{PP}$ supply voltage	$V_{PP}$	$V_{PP}$		12.2	12.5	12.8	V
$V_{DD}$ supply voltage	$V_{DD}$	$V_{CC}$		6.25	6.5	6.75	V
$V_{PP}$ supply current	$I_{PP}$	$I_{PP}$	$\overline{PGM} = V_{IL}$			50	mA
$V_{DD}$ supply current	$I_{DD}$	$I_{CC}$				50	mA

(2) PROM Read Mode ( $T_A = 25 \pm 5 \text{ }^\circ\text{C}$ ,  $V_{DD} = 5.0 \pm 0.5 \text{ V}$ ,  $V_{PP} = V_{DD} \pm 0.6 \text{ V}$ )

Parameter	Symbol	Symbol <sup>Note</sup>	Test Conditions	MIN.	TYP.	MAX.	Unit
Input voltage, high	$V_{IH}$	$V_{IH}$		$0.7 V_{DD}$		$V_{DD}$	V
Input voltage, low	$V_{IL}$	$V_{IL}$		0		$0.3 V_{DD}$	V
Output voltage, high	$V_{OH1}$	$V_{OH1}$	$I_{OH} = -1 \text{ mA}$	$V_{DD} - 1.0$			V
	$V_{OH2}$	$V_{OH2}$	$I_{OH} = -100 \text{ } \mu\text{A}$	$V_{DD} - 0.5$			V
Output voltage, low	$V_{OL}$	$V_{OL}$	$I_{OL} = 1.6 \text{ mA}$			0.4	V
Input leakage current	$I_{LI}$	$I_{LI}$	$0 \leq V_{IN} \leq V_{DD}$	-10		+10	μA
Output leakage current	$I_{LO}$	$I_{LO}$	$0 \leq V_{OUT} \leq V_{DD}$ , $\overline{OE} = V_{IH}$	-10		+10	μA
$V_{PP}$ supply voltage	$V_{PP}$	$V_{PP}$		$V_{DD} - 0.6$	$V_{DD}$	$V_{DD} + 0.6$	V
$V_{DD}$ supply voltage	$V_{DD}$	$V_{CC}$		4.5	5.0	5.5	V
$V_{PP}$ supply current	$I_{PP}$	$I_{PP}$	$V_{PP} = V_{DD}$			100	μA
$V_{DD}$ supply current	$I_{DD}$	$I_{CCA1}$	$\overline{CE} = V_{IL}$ , $V_{IN} = V_{IH}$			50	mA

**Note** Corresponding μPD27C1001A symbol.



AC CHARACTERISTICS

(1) PROM Write Mode

(a) Page program mode ( $T_A = 25 \pm 5 \text{ }^\circ\text{C}$ ,  $V_{DD} = 6.5 \pm 0.25 \text{ V}$ ,  $V_{PP} = 12.5 \pm 0.3 \text{ V}$ )

Parameter	Symbol	Symbol <sup>Note</sup>	Test Conditions	MIN.	TYP.	MAX.	Unit
Address setup time (to $\overline{OE} \downarrow$ )	t <sub>AS</sub>	t <sub>AS</sub>		2			μs
$\overline{OE}$ setup time	to <sub>ES</sub>	to <sub>ES</sub>		2			μs
$\overline{CE}$ setup time (to $\overline{OE} \downarrow$ )	tc <sub>ES</sub>	tc <sub>ES</sub>		2			μs
Input data setup time (to $\overline{OE} \downarrow$ )	td <sub>S</sub>	td <sub>S</sub>		2			μs
Address hold time (from $\overline{OE} \uparrow$ )	t <sub>AH</sub>	t <sub>AH</sub>		2			μs
	t <sub>AHL</sub>	t <sub>AHL</sub>		2			μs
	t <sub>AHV</sub>	t <sub>AHV</sub>		0			μs
Input data hold time (from $\overline{OE} \uparrow$ )	td <sub>H</sub>	td <sub>H</sub>		2			μs
Data output float delay time from $\overline{OE} \uparrow$	td <sub>F</sub>	td <sub>F</sub>		0		250	ns
V <sub>PP</sub> setup time (to $\overline{OE} \downarrow$ )	tv <sub>PS</sub>	tv <sub>PS</sub>		1.0			ms
V <sub>DD</sub> setup time (to $\overline{OE} \downarrow$ )	tv <sub>DS</sub>	tv <sub>CS</sub>		1.0			ms
Program pulse width	tp <sub>W</sub>	tp <sub>W</sub>		0.095	0.1	0.105	ms
Valid data delay time from $\overline{OE} \downarrow$	to <sub>E</sub>	to <sub>E</sub>				1	μs
$\overline{OE}$ pulse width during data latching	tl <sub>W</sub>	tl <sub>W</sub>		1			μs
$\overline{PGM}$ setup time	tp <sub>GM<math>\overline{S}</math></sub>	tp <sub>GM<math>\overline{S}</math></sub>		2			μs
$\overline{CE}$ hold time	tc <sub>EH</sub>	tc <sub>EH</sub>		2			μs
$\overline{OE}$ hold time	to <sub>EH</sub>	to <sub>EH</sub>		2			μs

(b) Byte program mode ( $T_A = 25 \pm 5 \text{ }^\circ\text{C}$ ,  $V_{DD} = 6.5 \pm 0.25 \text{ V}$ ,  $V_{PP} = 12.5 \pm 0.3 \text{ V}$ )

Parameter	Symbol	Symbol <sup>Note</sup>	Test Conditions	MIN.	TYP.	MAX.	Unit
Address setup time (to $\overline{PGM} \downarrow$ )	t <sub>AS</sub>	t <sub>AS</sub>		2			μs
$\overline{OE}$ set time	to <sub>ES</sub>	to <sub>ES</sub>		2			μs
$\overline{CE}$ setup time (to $\overline{PGM} \downarrow$ )	tc <sub>ES</sub>	tc <sub>ES</sub>		2			μs
Input data setup time (to $\overline{PGM} \downarrow$ )	td <sub>S</sub>	td <sub>S</sub>		2			μs
Address hold time (from $\overline{OE} \uparrow$ )	t <sub>AH</sub>	t <sub>AH</sub>		2			μs
Input data hold time (from $\overline{PGM} \uparrow$ )	td <sub>H</sub>	td <sub>H</sub>		2			μs
Data output float delay time from $\overline{OE} \uparrow$	td <sub>F</sub>	td <sub>F</sub>		0		250	ns
V <sub>PP</sub> setup time (to $\overline{PGM} \downarrow$ )	tv <sub>PS</sub>	tv <sub>PS</sub>		1.0			ms
V <sub>DD</sub> setup time (to $\overline{PGM} \downarrow$ )	tv <sub>DS</sub>	tv <sub>CS</sub>		1.0			ms
Program pulse width	tp <sub>W</sub>	tp <sub>W</sub>		0.095	0.1	0.105	ms
Valid data delay time from $\overline{OE} \downarrow$	to <sub>E</sub>	to <sub>E</sub>				1	μs
$\overline{OE}$ hold time	to <sub>EH</sub>	—		2			μs

**Note** Corresponding μPD27C1001A symbol.

**(2) PROM Read Mode ( $T_A = 25 \pm 5 \text{ }^\circ\text{C}$ ,  $V_{DD} = 5.0 \pm 0.5 \text{ V}$ ,  $V_{PP} = V_{DD} \pm 0.6 \text{ V}$ )**

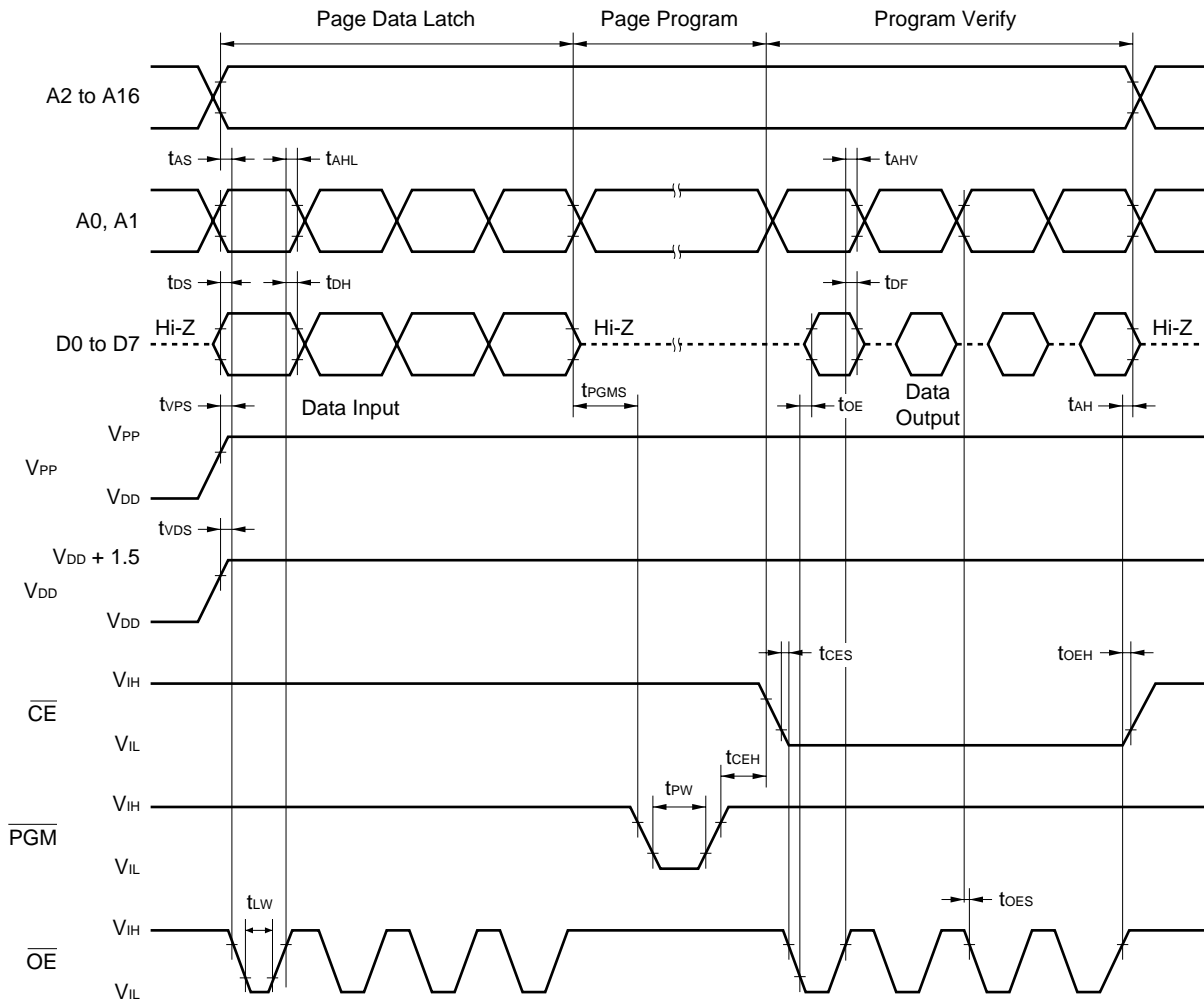
Parameter	Symbol	Symbol Note	Test Conditions	MIN.	TYP.	MAX.	Unit
Data output delay time from address	$t_{ACC}$	$t_{ACC}$	$\overline{CE} = \overline{OE} = V_{IL}$			800	ns
Data output delay time $\overline{CE} \downarrow$	$t_{CE}$	$t_{CE}$	$\overline{OE} = V_{IL}$			800	ns
Data output delay time $\overline{OE} \downarrow$	$t_{OE}$	$t_{OE}$	$\overline{CE} = V_{IL}$			200	ns
Data output float delay time from $\overline{OE} \uparrow$	$t_{DF}$	$t_{DF}$	$\overline{CE} = V_{IL}$	0		60	ns
Data hold time to address	$t_{OH}$	$t_{OH}$	$\overline{CE} = \overline{OE} = V_{IL}$	0			ns

**Note** Corresponding μPD27C1001A symbol.

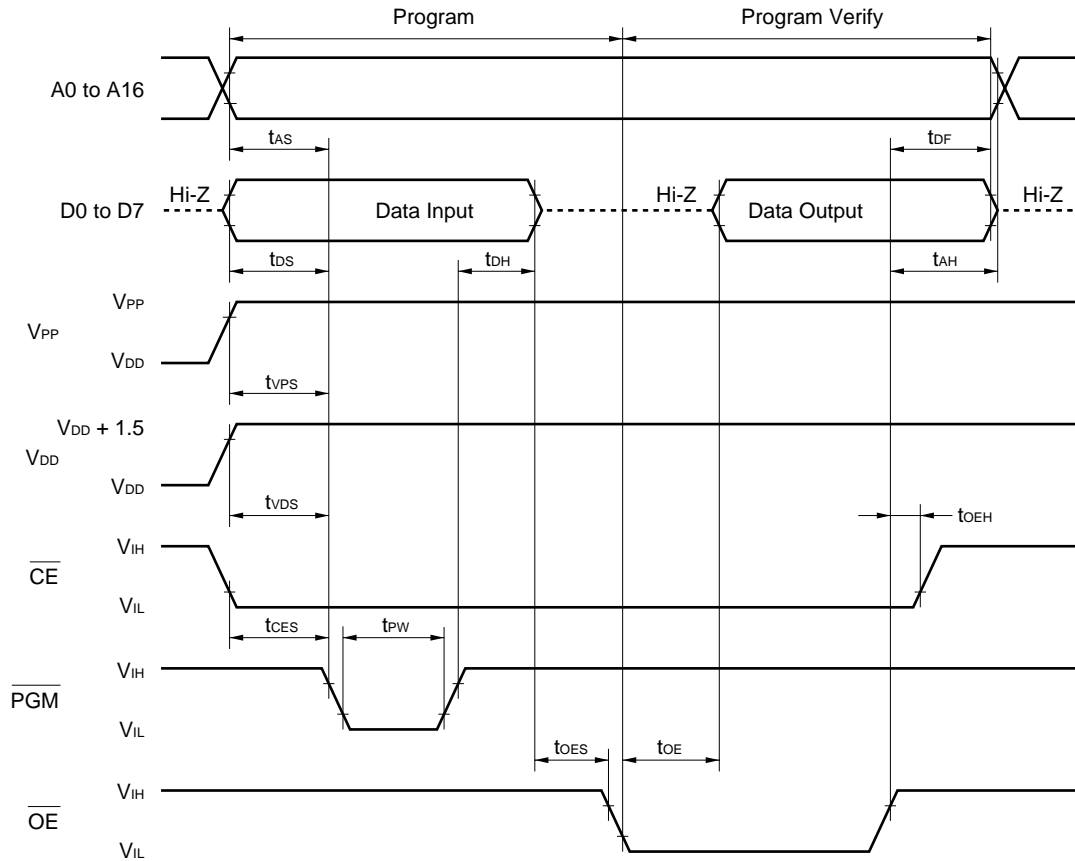
**(3) PROM Programming Mode Setting ( $T_A = 25 \text{ }^\circ\text{C}$ ,  $V_{SS} = 0 \text{ V}$ )**

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
PROM programming mode setup time	$t_{SMA}$		10			μs

PROM Write Mode Timing (page program mode)

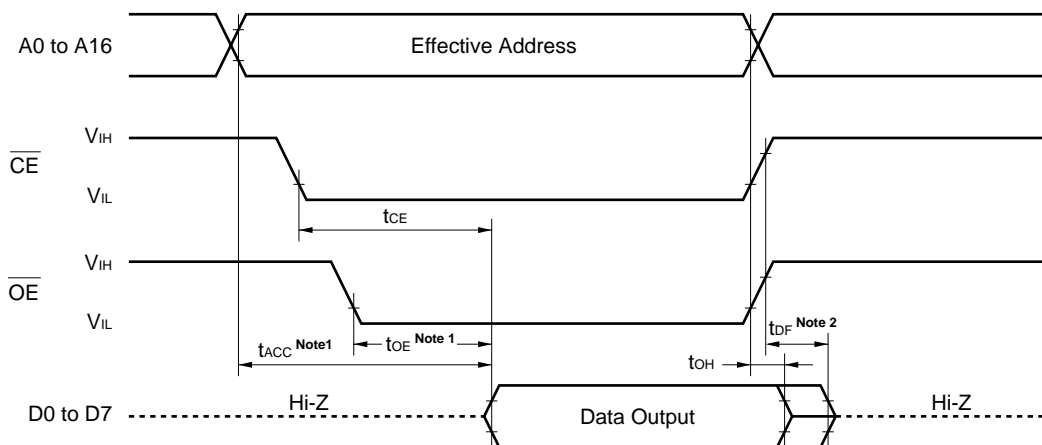


**PROM Write Mode Timing (byte program mode)**



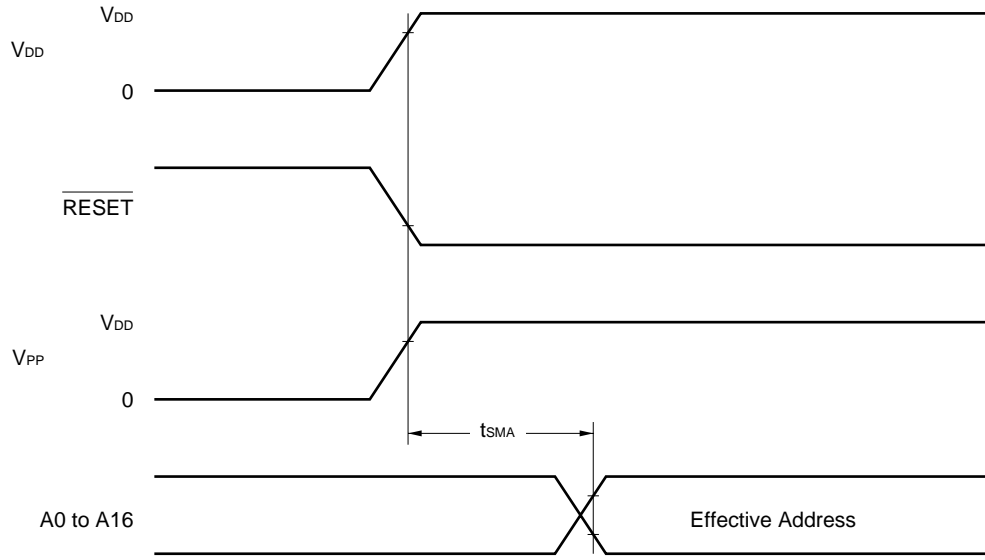
- Cautions**
1.  $V_{DD}$  should be applied before  $V_{PP}$ , and removed after  $V_{PP}$ .
  2.  $V_{PP}$  must not exceed +13.5 V including overshoot.
  3. Reliability may be adversely affected if removal/reinsertion is performed while +12.5 V is being applied to  $V_{PP}$ .

**PROM Read Mode Timing**



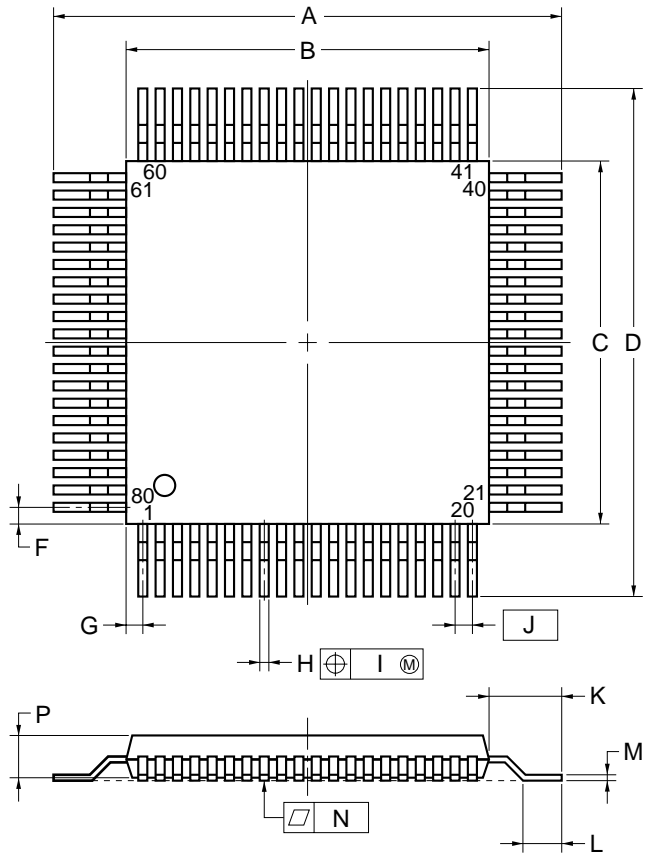
- Notes**
1. If you want to read within the range of  $t_{ACC}$ , make the  $\overline{OE}$  input delay time from the fall of  $\overline{CE}$  a maximum of  $t_{ACC} - t_{OE}$ .
  2.  $t_{DF}$  is the time from when either  $\overline{OE}$  or  $\overline{CE}$  first reaches  $V_{IH}$ .

PROM Programming Mode Setting Timing

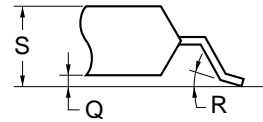


7. PACKAGE DRAWINGS

80 PIN PLASTIC QFP (14×14)



detail of lead end



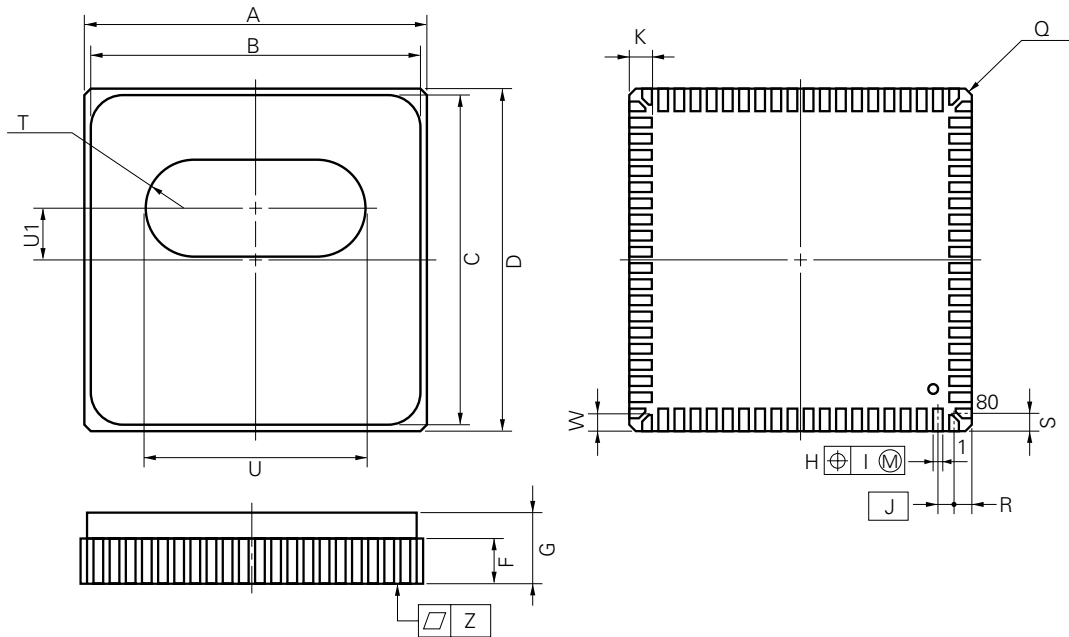
NOTE

Each lead centerline is located within 0.13 mm (0.005 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
A	17.2±0.4	0.677±0.016
B	14.0±0.2	0.551 <sup>+0.009</sup> <sub>-0.008</sub>
C	14.0±0.2	0.551 <sup>+0.009</sup> <sub>-0.008</sub>
D	17.2±0.4	0.677±0.016
F	0.825	0.032
G	0.825	0.032
H	0.30±0.10	0.012 <sup>+0.004</sup> <sub>-0.005</sub>
I	0.13	0.005
J	0.65 (T.P.)	0.026 (T.P.)
K	1.6±0.2	0.063±0.008
L	0.8±0.2	0.031 <sup>+0.009</sup> <sub>-0.008</sub>
M	0.15 <sup>+0.10</sup> <sub>-0.05</sub>	0.006 <sup>+0.004</sup> <sub>-0.003</sub>
N	0.10	0.004
P	2.7	0.106
Q	0.1±0.1	0.004±0.004
R	5°±5°	5°±5°
S	3.0 MAX.	0.119 MAX.

S80GC-65-3B9-4

80 PIN CERAMIC WQFN



**NOTE**

Each lead centerline is located within 0.06 mm (0.003 inch) of its true position (T.P.) at maximum material condition.

X80KW-65A-1

ITEM	MILLIMETERS	INCHES
A	14.0±0.2	0.551±0.008
B	13.6	0.535
C	13.6	0.535
D	14.0±0.2	0.551±0.008
F	1.84	0.072
G	3.6 MAX.	0.142 MAX.
H	0.45±0.10	0.018 <sup>+0.004</sup> <sub>-0.005</sub>
I	0.06	0.003
J	0.65 (T.P.)	0.024 (T.P.)
K	1.0±0.15	0.039 <sup>+0.007</sup> <sub>-0.006</sub>
Q	C 0.3	C 0.012
R	0.825	0.032
S	0.825	0.032
T	R 2.0	R 0.079
U	9.0	0.354
U1	2.1	0.083
W	0.75±0.15	0.030 <sup>+0.006</sup> <sub>-0.007</sub>
Z	0.10	0.004

**APPENDIX A. DIFFERENCES BETWEEN μPD178018A AND μPD178018 SUBSERIES**

Product Name		μPD178018A Subseries				μPD178018 Subseries			
		μPD178004A	μPD178006A	μPD178016A	μPD178018A μPD178P018A <sup>Note</sup>	μPD178004	μPD178006	μPD178016	μPD178018 μPD178P018
Item	PLL frequency synthesizer	Reference frequency				Reference frequency			
		7 types selectable by program (1, 3, 5, 9, 10, 25, 50 kHz)				11 types selectable by program (1, 1.25, 2.5, 3, 5, 6.25, 9, 10, 12.5, 25, 50 kHz)			
		EO0 pin output format				Buffer type			
		EO1 pin output format				Buffer type		Constant-current power supply type	
	EO1 pin high-impedance function	Not supported		Supported		Not supported			

**Note** Under development

**Remark** The mask ROM of mask versions (μPD178018A and μPD178018) is replaced with one-time PROM or EPROM in the one-time PROM versions (μPD178P018A and μPD178P018).



**APPENDIX B. DEVELOPMENT TOOLS**

The following development tools are available for system development using the μPD178P018A Subseries.

**Language Processing Software**

RA78K/0 <small>Notes 1, 2, 3, 4</small>	78K/0 Series common assembler package
CC78K/0 <small>Notes 1, 2, 3, 4</small>	78K/0 Series common C compiler package
DF178018 <small>Notes 1, 2, 3, 4, 8</small>	μPD178018A Subseries common device file
CC78K/0-L <small>Notes 1, 2, 3, 4</small>	78K/0 Series common C compiler library source file

**PROM Writing Tools**

PG-1500	PROM writer
PG-178P018GC	Program writer adapters connected to a PG-1500
PA-178P018KK-T	
PG-1500 controller <small>Notes 1, 2</small>	PG-1500 control program

**Debugging Tools**

IE-78000-R	In-circuit emulator common to 78K/0 Series
IE-78000-R-A	In-circuit emulator common to 78K/0 Series (for the integrated debugger)
IE-78000-R-BK	Break board common to 78K/0 Series
IE-178018-R-EM	Emulation board common to μPD178018A Subseries
IE-78000-R-SV3	Interface adapter and cable when using EWS as a host machine (for IE-78000-R-A)
IE-70000-98-IF-B	Interface adapter when using the PC-9800 Series (except notebooks) as a host machine (for IE-78000-R-A)
IE-70000-98N-IF	Interface adapter and cable when using the PC-9800 Series notebook as a host machine (for IE-78000-R-A)
IE-70000-PC-IF-B	Interface adapter when using IBM PC/AT™ as a host machine (for IE-78000-R-A)
EP-78230GC-R	Emulation probe common to μPD78234 Subseries
EV-9200GC-80	Socket for mounting on target system board created for 80-pin plastic QFP (GC-3B9 type)
EV-9900	Jig used when removing the μPD178P018AKK-T from the EV-9200GC-80.
SM78K0 <small>Notes 5, 6, 7</small>	78K/0 series common system simulator
ID78K0 <small>Notes 4, 5, 6, 7</small>	Integrated debugger for IE-78000-R-A
SD78K/0 <small>Notes 1, 2</small>	IE-78000-R screen debugger
DF178018 <small>Notes 1, 2, 4, 5, 6, 7, 8</small>	μPD178018A Subseries device file

**Real-Time OS**

RX78K/0 <small>Notes 1, 2, 3, 4</small>	78K/0 Series real-time OS
MX78K0 <small>Notes 1, 2, 3, 4</small>	78K/0 Series OS

- Notes**
1. PC-9800 Series (MS-DOS™) based
  2. IBM PC/AT and compatibles (PC DOS™/IBM DOS™/MS-DOS) based
  3. HP9000 Series 300™ (HP-UX™) based
  4. HP9000 Series 700™ (HP-UX™) based, SPARCstation™ (SunOS™) based, EWS4800 Series (EWS-UX/V) based
  5. PC-9800 Series (MS-DOS + Windows™) based
  6. IBM PC/AT and compatibles (PC DOS/IBM DOS/MS-DOS + Windows) based
  7. NEWS™ (NEWS-OS™) based
  8. Under development

**Fuzzy Inference Development Support System**

FE9000 <small>Note 1</small> /FE9200 <small>Note 2</small>	Fuzzy knowledge data creation tool
FT9080 <small>Note 1</small> /FT9085 <small>Note 3</small>	Translator
FI78K0 <small>Notes 1, 3</small>	Fuzzy inference module
FD78K0 <small>Notes 1, 3</small>	Fuzzy inference debugger

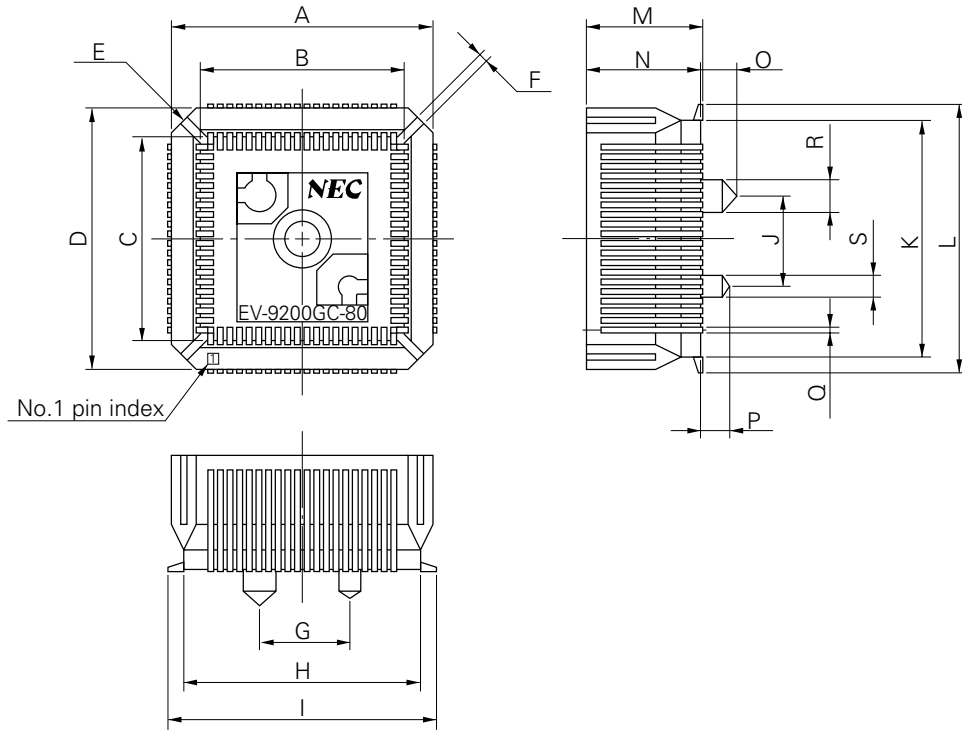
- Notes**
1. PC-9800 Series (MS-DOS) based
  2. IBM PC/AT and its compatibles (PC DOS/IBM DOS/MS-DOS + Windows) based
  3. IBM PC/AT and its compatibles (PC DOS/IBM DOS/MS-DOS) based

- Remarks**
1. Please refer to the **78K/0 Series Selection Guide (U11126E)** for information on third party development tools.
  2. The RA78K/0, CC78K/0, SD78K/0, ID78K/0, SM78K/0, and RX78K/0 are used in combination with the DF178018.

CONVERSION SOCKET DRAWING AND RECOMMENDED FOOTPRINT

Figure B-1. Drawing of EV-9200GC-80 (for Reference only)

Based on EV-9200GC-80  
 (1) Package drawing (in mm)

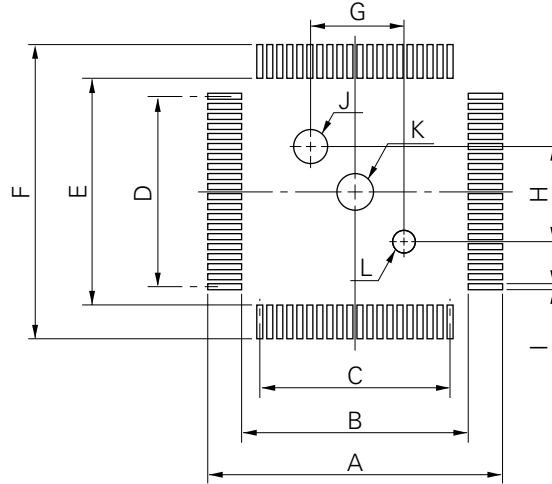


EV-9200GC-80-G1E

ITEM	MILLIMETERS	INCHES
A	18.0	0.709
B	14.4	0.567
C	14.4	0.567
D	18.0	0.709
E	4-C 2.0	4-C 0.079
F	0.8	0.031
G	6.0	0.236
H	16.0	0.63
I	18.7	0.736
J	6.0	0.236
K	16.0	0.63
L	18.7	0.736
M	8.2	0.323
N	8.0	0.315
O	2.5	0.098
P	2.0	0.079
Q	0.35	0.014
R	φ2.3	φ0.091
S	φ1.5	φ0.059

Figure B-2. Recommended Footprint of EV-9200GC-80 (for Reference only)

Based on EV-9200GC-80  
(2) Pad drawing (in mm)



EV-9200GC-80-P1E

ITEM	MILLIMETERS	INCHES
A	19.7	0.776
B	15.0	0.591
C	$0.65 \pm 0.02 \times 19 = 12.35 \pm 0.05$	$0.026^{+0.001}_{-0.002} \times 0.748 = 0.486^{+0.003}_{-0.002}$
D	$0.65 \pm 0.02 \times 19 = 12.35 \pm 0.05$	$0.026^{+0.001}_{-0.002} \times 0.748 = 0.486^{+0.003}_{-0.002}$
E	15.0	0.591
F	19.7	0.776
G	$6.0 \pm 0.05$	$0.236^{+0.003}_{-0.002}$
H	$6.0 \pm 0.05$	$0.236^{+0.003}_{-0.002}$
I	$0.35 \pm 0.02$	$0.014^{+0.001}_{-0.001}$
J	$\phi 2.36 \pm 0.03$	$\phi 0.093^{+0.001}_{-0.002}$
K	$\phi 2.3$	$\phi 0.091$
L	$\phi 1.57 \pm 0.03$	$\phi 0.062^{+0.001}_{-0.002}$

**Caution** Dimensions of mount pad for EV-9200 and that for target device (QFP) may be different in some parts. For the recommended mount pad dimensions for QFP, refer to "SEMICONDUCTOR DEVICE MOUNTING TECHNOLOGY MANUAL" (C10535E).

APPENDIX C. RELATED DOCUMENTS

Device Documents

Title		Document No. (Japanese)	Document No. (English)
μPD178018A Subseries User's Manual		To be prepared	To be prepared
78K/0 Series User's Manual—Instruction		U12326J	U12326E
78K/0 Series Instruction Set		U10904J	—
78K/0 Series Instruction Table		U10903J	—
μPD178018A Subseries Special Function Register Table		To be prepared	—
78K/0 Series Application Note	Basics (II)	U10121J	U10121E

Development Tool Documents (User's Manual)

Title		Document No. (Japanese)	Document No. (English)
RA78K Series Assembler Package	Operation	EEU-809	EEU-1399
	Language	EEU-815	EEU-1404
RA78K Series Structured Assembler Preprocessor		EEU-817	EEU-1402
RA78K0 Assembler Package	Operation	U11802J	U11802E
	Assembly Language	U11801J	U11801E
	Structured Assembly Language	U11789J	U11789E
CC78K Series C Compiler	Operation	EEU-656	EEU-1280
	Language	EEU-655	EEU-1284
CC78K/0 C Compiler	Operation	U11517J	U11517E
	Language	U11518J	U11518E
CC78K/0 C Compiler Application Notes	Programming Know-how	EEA-618	EEA-1208
CC78K Series Library Source File		U12322J	—
PG-1500 PROM Programmer		U11940J	EEU-1335
PG-1500 Controller PC-9800 Series (MS-DOS) Based		EEU-704	EEU-1291
PG-1500 Controller IBM PC Series (PC DOS) Based		EEU-5008	U10540E
IE-78000-R		U11376J	U11376E
IE-78000-R-A		U10057J	U10057E
IE-78000-R-BK		EEU-867	EEU-1427
IE-178018-R-EM		U10668J	U10668E
EP-78230		EEU-985	EEU-1515
SM78K0 System Simulator Windows Based	Reference	U10181J	U10181E
SM78K Series System Simulator	External Parts User open Interface Specifications	U10092J	U10092E
ID78K0 Integrated Debugger EWS Based	Reference	U11151J	U11151E
ID78K0 Integrated Debugger PC Based	Reference	U11539J	U11539E
ID78K0 Integrated Debugger Windows Based	Guide	U11649J	U11649E
SD78K/0 Screen Debugger PC-9800 Series (MS-DOS) Based	Introduction	EEU-852	U10539E
	Reference	U10952J	—
SD78K/0 Screen Debugger IBM PC/AT (PC DOS) Based	Introduction	EEU-5024	EEU-1414
	Reference	U11279J	U11279E

**Caution** The contents of the above documents are subject to change without notice. Please ensure that the latest versions are used in design work, etc.

### Related Documents for Embedded Software (User's Manual)

Title		Document No. (Japanese)	Document No. (English)
78K/0 Series Realtime OS	Basics	U11537J	—
	Installation	U11536J	—
78K/0 Series OS MX78K0	Basics	U12257J	—
Fuzzy Knowledge Data Creation Tool		EEU-829	EEU-1438
78K/0, 78K/II, 87AD Series Fuzzy Inference Development Support System—Translator		EEU-862	EEU-1444
78K/0 Series Fuzzy Inference Development Support System—Fuzzy Inference Module		EEU-858	EEU-1441
78K/0 Series Fuzzy Inference Development Support System —Fuzzy Inference Debugger		EEU-921	EEU-1458

### Other Documents

Title	Document No. (Japanese)	Document No. (English)
IC Package Manual	C10943X	
Semiconductor Device Mounting Technology Manual	C10535J	C10535E
Quality Guides on NEC Semiconductor Devices	C11531J	C11531E
NEC Semiconductor Device Reliability and Quality Control System	C10983J	C10983E
Electrostatic Discharge (ESD) Test	MEM-539	—
Semiconductor Device Quality Assurance Guide	C11893J	MEI-1202
Microcomputer-related Product Guide (Products by other Manufacturers)	U11416J	—

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[MEMO]

[MEMO]



[MEMO]

## NOTES FOR CMOS DEVICES

### ① PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

**Note:** Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

### ② HANDLING OF UNUSED INPUT PINS FOR CMOS

**Note:** No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS device behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to  $V_{DD}$  or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

### ③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

**Note:** Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

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- Ordering information
- Product release schedule
- Availability of related technical literature
- Development environment specifications (for example, specifications for third-party tools and components, host computers, power plugs, AC supply voltages, and so forth)
- Network requirements

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Special: Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)

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